

Results on 3D Pixel Sensors for the CMS Inner Tracker

Upgrade at the High Luminosity LHC



This project has received funding from the European Union's Horizon 2020 Research and Innovation programme under Grant Agreement no. 654168.

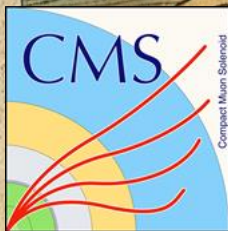
Antonio Cassese

INFN - Sezione di Firenze
on behalf of the CMS Tracker Group

"Trento" Workshop on Advanced Silicon Radiation Detectors Physics

17th-19th February 2020

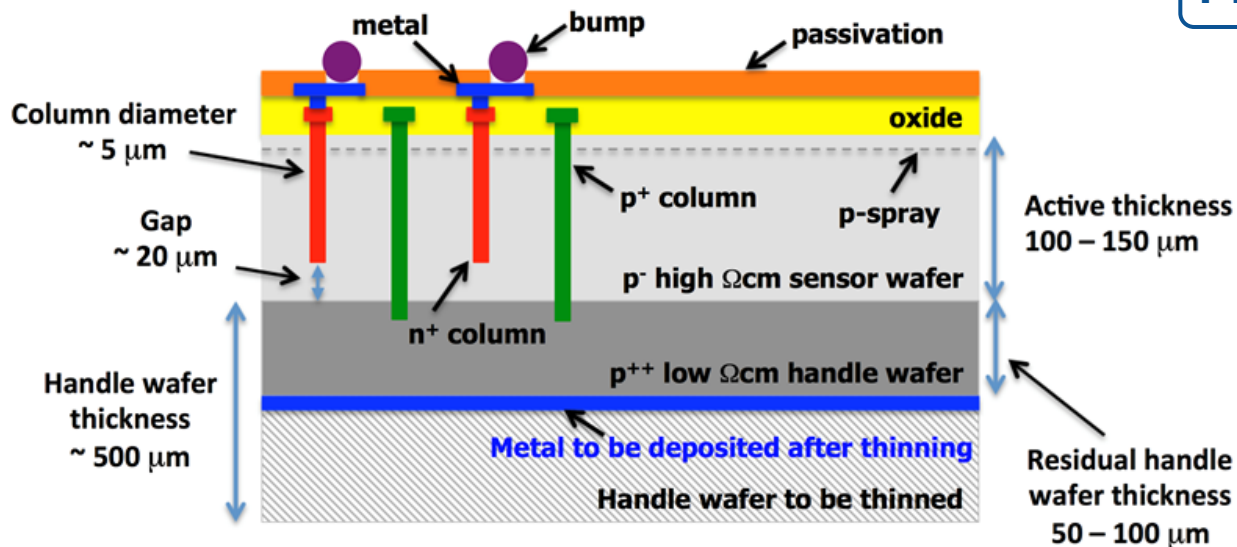
Vienna - Austria



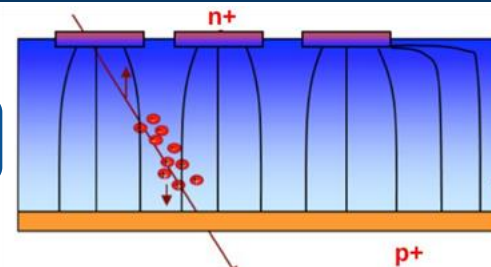
Introduction

- I will not talk about details of CMS Inner Tracker: there are excellent talks on the subject at this workshop!
- ✓ Jory Sonneveld talk (17th Feb 2020, 12:55): “The CMS Pixel Detector for the High Luminosity LHC” <https://indico.cern.ch/event/813597/contributions/3727821/>
 - ✓ Corrinne Mills talk (17th Feb 2020, 15:15): “Performance of highly irradiated pixel sensors for the CMS HL-LHC upgrade”
<https://indico.cern.ch/event/813597/contributions/3727828/>
 - ✓ Finn Feindt talk (17th Feb 2020, 15:55): “Test Beam Characterization of Planar Pixel Sensors for the CMS Phase 2 Upgrade”
<https://indico.cern.ch/event/813597/contributions/3727834/>
 - ✓ Jordi Duarte Campderros talk (19th Feb 2020, 10:00): “Study of 3D pixel sensors after non-uniform proton irradiation”
<https://indico.cern.ch/event/813597/contributions/3727824/>
 - ✓ Roberto Seidita talk (19th Feb 2020, 16:00): “Serial powering at CMS silicon tracker detector for High Luminosity Upgrade”
<https://indico.cern.ch/event/813597/contributions/3727820/>

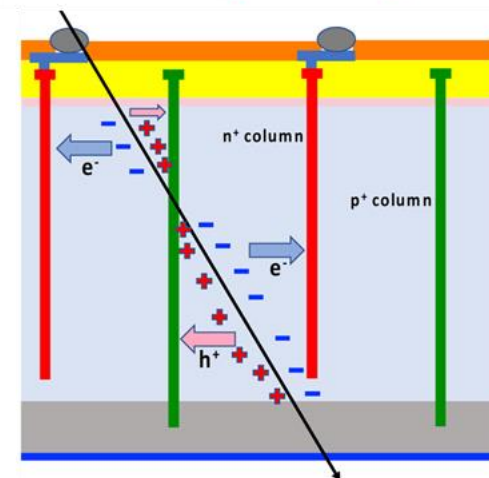
3D pixel sensors



Planar



3D



- 3D pixel R&D (FBK & CNM)

- In 3D sensors the drift path is perpendicular to the active depth

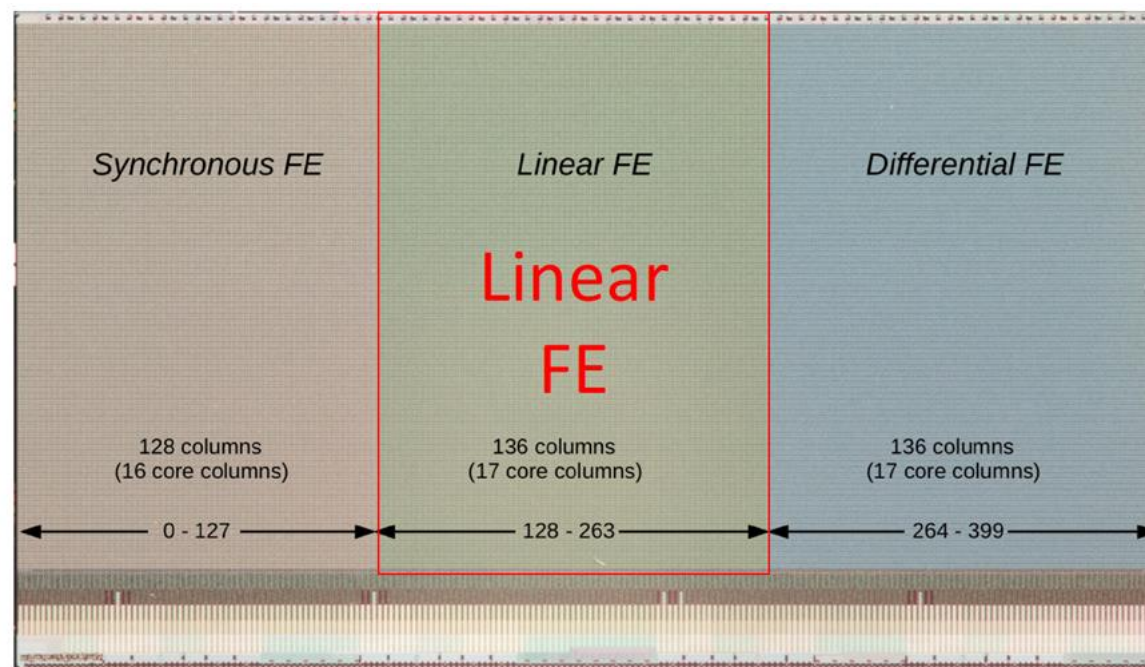
- Short drift distance $\rightarrow \sim 30 \div 50 \mu\text{m}$ (3D) vs $100 \div 150 \mu\text{m}$ (Planar)

- Many advantages with respect to planar sensors:

- Smaller bias voltage needed to deplete the sensor (5 V before and ~ 150 V after irradiation)
- Less trapping in irradiated sensors (shorter drift distance!)
- Slim edges, i.e. smaller dead zones
- Same charge produced

- Promising candidates for the high radiation environment of the inner layers and rings

RD53: the inner tracker readout chip



RD53A first prototype of ROC

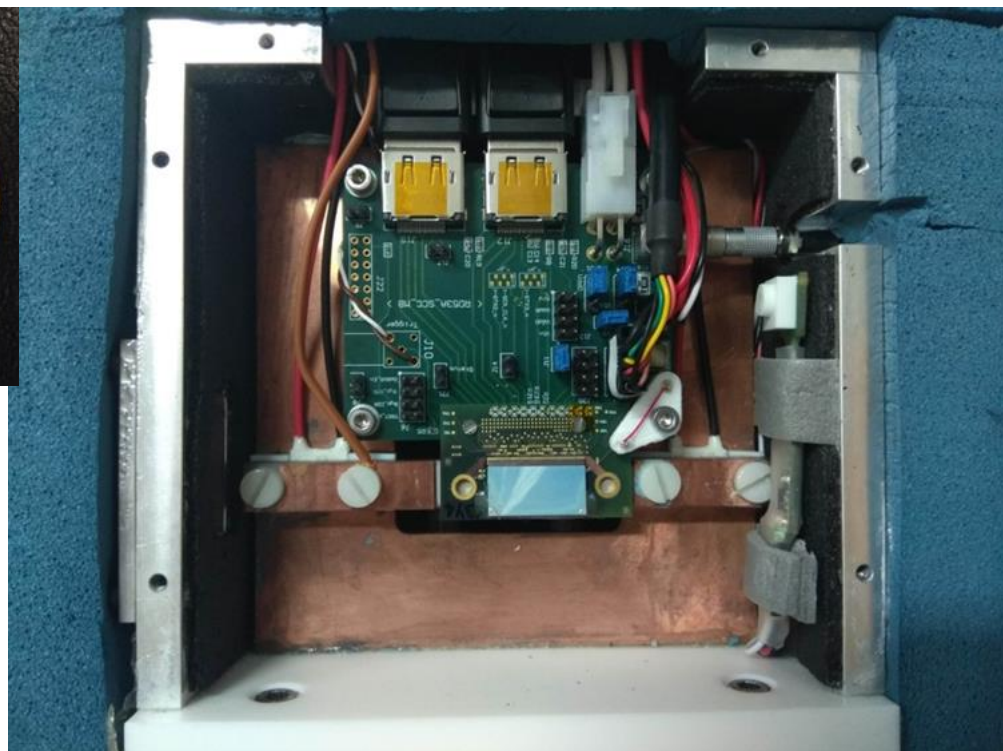
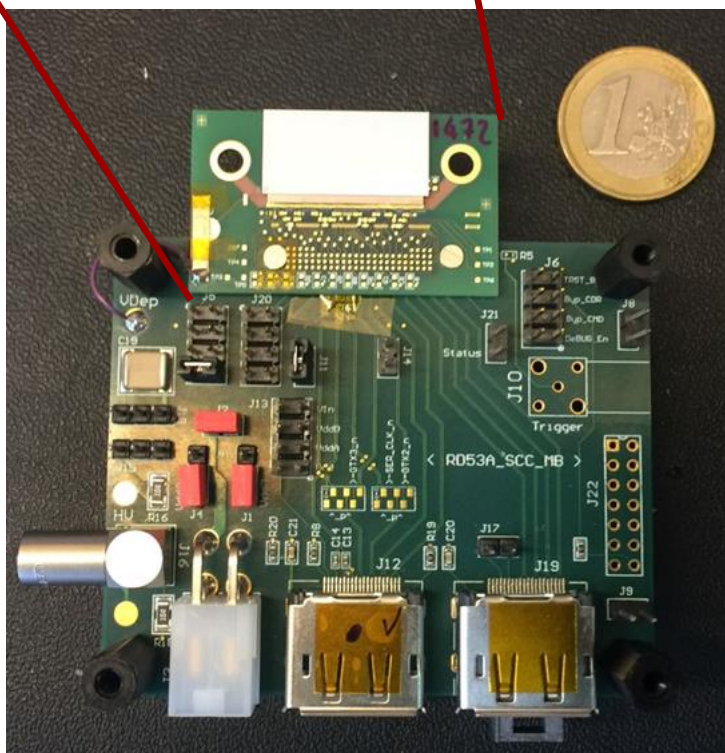
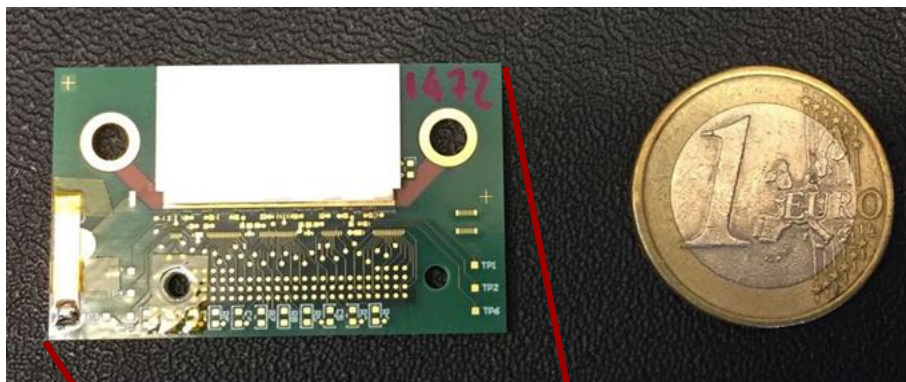
- ½ total size (**50×50 μm^2 cell**, 65 CMOS nm technology)
- Used for **R&D**
- 3 analog Front-Ends (Synchronous, **Linear**, Differential)
- Time over Threshold counter to measure charge (4 bits); caveat **ToT as charge unit**
- CMS choice: **Linear F.E.**
- **Low threshold and noise, radiation hard** (proven up to at least **5 MGy**)
- **All results presented here obtained using Linear F.E. (central section)**

Test beam setup @DESY in 2019

- **Beam:** 5.2 GeV electrons
- **Telescope:** Mimosa
 - 3 planes before DUT (Device Under Test)
 - 3 planes after DUT
 - Spatial resolution up to $\sim 3.8 \mu\text{m}$, depends on telescope and geometry configuration
- **Single Chip Modules on beam:**
 - Two FBK mask aligner fresh 3D sensors
 - 130 μm active thickness
 - One $50 \times 50 \mu\text{m}^2$, One $25 \times 100 \mu\text{m}^2$ pitch
 - Bump bonded at IZM (Germany)
 - One FBK stepper fresh 3D sensor
 - 150 μm active thickness
 - $50 \times 50 \mu\text{m}^2$ pitch
 - Indium bump bonded at Leonardo (Italy)
 - One FBK irradiated 3D sensor
 - 130 μm active thickness
 - $50 \times 50 \mu\text{m}^2$ pitch
 - Irradiated @CERN
 - Nominal fluence $1 \times 10^{16} \text{ n}_{\text{eq}} \text{ cm}^{-2}$



Test beam setup @DESY in 2019



- Sensors bump-bonded to RD53A
- Mounted on RICE cards
- BDAQ (<https://gitlab.cern.ch/silab/bdaq53>)
- Irradiated sensor kept inside a cooling box:
 - Stable temperature of -27°C
 - Telescope resolution worsen ($\sim 10 \mu\text{m}$)

Modules: data taking and results

FRESH

- Two HV bias point:
 - 6 V (minimum allowed by PS)
 - 30 V
- All modules tuned to $\sim 900 e^-$ threshold

IRRADIATED

- Bias scan
 - $> 20V$
 - $< 150 V$
- Tuned to $1100 e^-$ threshold

- Low voltage powering via RD53A LDO integrated circuit
- “Reference” hit efficiency measured for perpendicular tracks (effect of columnar electrodes)
- Cluster size studies and angle scan for spatial resolution measurements
- 24 V of bias voltage range with same performances guarantees a good behaviour with SP*

Module	Leakage Current @Bias Voltage Measured @ DESY TB, T = 45°C	Efficiency (Orthogonal Tracks)
3D Mask Aligner - $50 \times 50 \mu\text{m}^2$	150 nA @6 V - 250 nA @30 V	> 99%
3D Mask Aligner - $25 \times 100 \mu\text{m}^2$	130 nA @6 V - 190 nA @30 V	> 99%
3D Stepper - $50 \times 50 \mu\text{m}^2$	6.5 μA @6 V - 16.5 μA @ 30 V	> 99%
3D irradiated - $50 \times 50 \mu\text{m}^2$	120 μA @ 120 V	98.8% @146 V

Modules: data taking and results

FRESH

- Two HV bias point:
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 - 30 V
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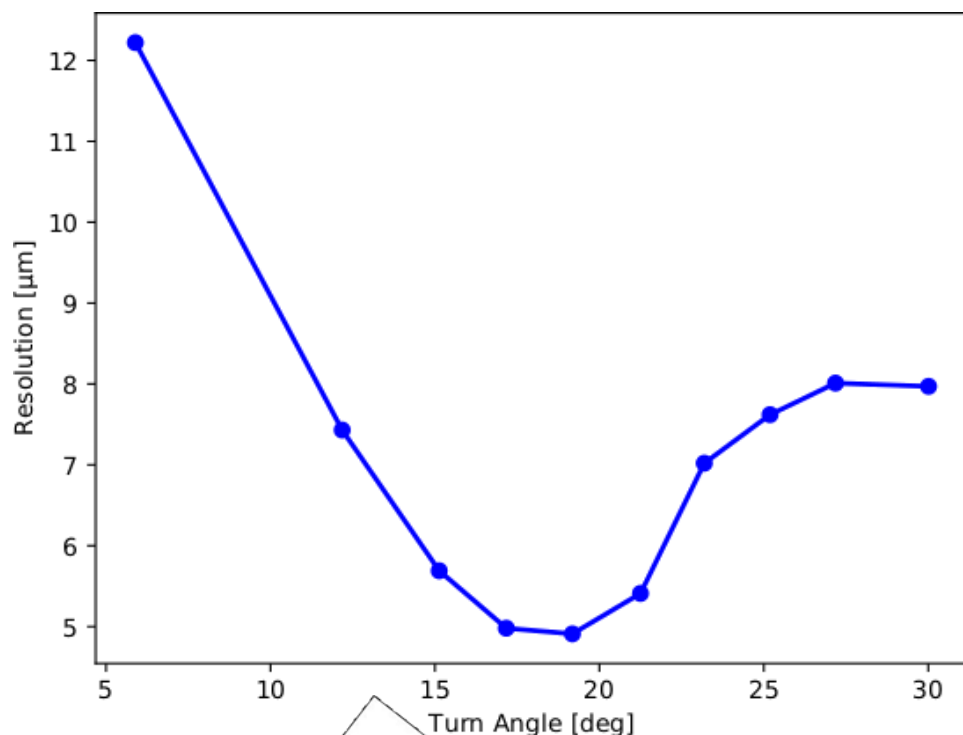
*See Roberto Seidita’s talk (19th Feb 2020, 16:00):

“Serial powering at CMS silicon tracker detector for High Luminosity Upgrade”

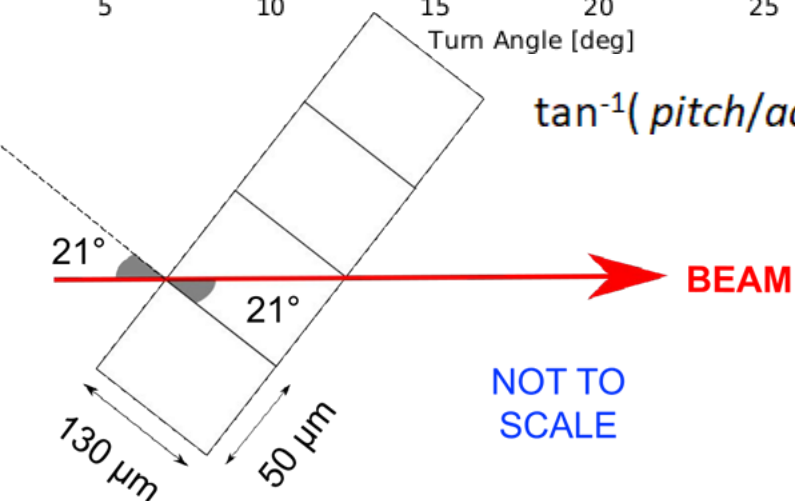
<https://indico.cern.ch/event/813597/contributions/3727820/>

Module	Leakage Current @Bias Voltage Measured @ DESY TB, T = 45°C	Efficiency (Orthogonal Tracks)
3D Mask Aligner - 50x50 μm^2	150 nA @6 V - 250 nA @30 V	> 99%
3D Mask Aligner - 25x100 μm^2	130 nA @6 V - 190 nA @30 V	> 99%
3D Stepper - 50x50 μm^2	6.5 μA @6 V - 16.5 μA @ 30 V	> 99%
3D irradiated - 50x50 μm^2	120 μA @ 120 V	98.8% @146 V

Resolution vs Turning angle: $50 \times 50 \mu\text{m}^2$



- Telescope resolution (σ_{tele}) subtracted in quadrature from DUT residual using both triplets
- σ_{tele} goes from $3.8 \mu\text{m}$ to $6.2 \mu\text{m}$ (depends on telescope configuration, mainly distance between first and second MIMOSA triplets)
- Best $\sigma_{\text{DUT}} \sim 5 \mu\text{m}$ @ $\sim 19^\circ$ (expected value compatible)
- In most of the angular range σ_{DUT} is $8 \mu\text{m}$ or better

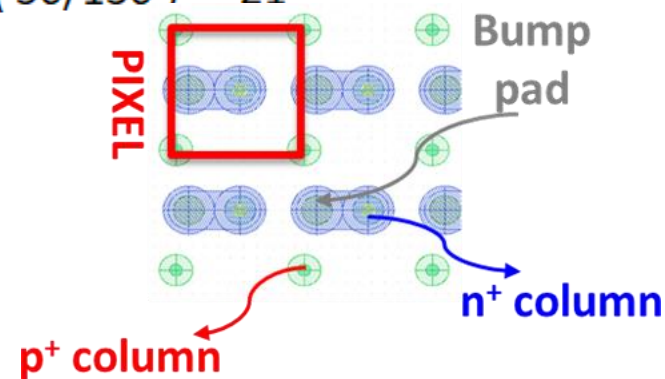


$$\tan^{-1}(\text{pitch}/\text{active_thickness}) = \tan^{-1}(50/130) \simeq 21^\circ$$

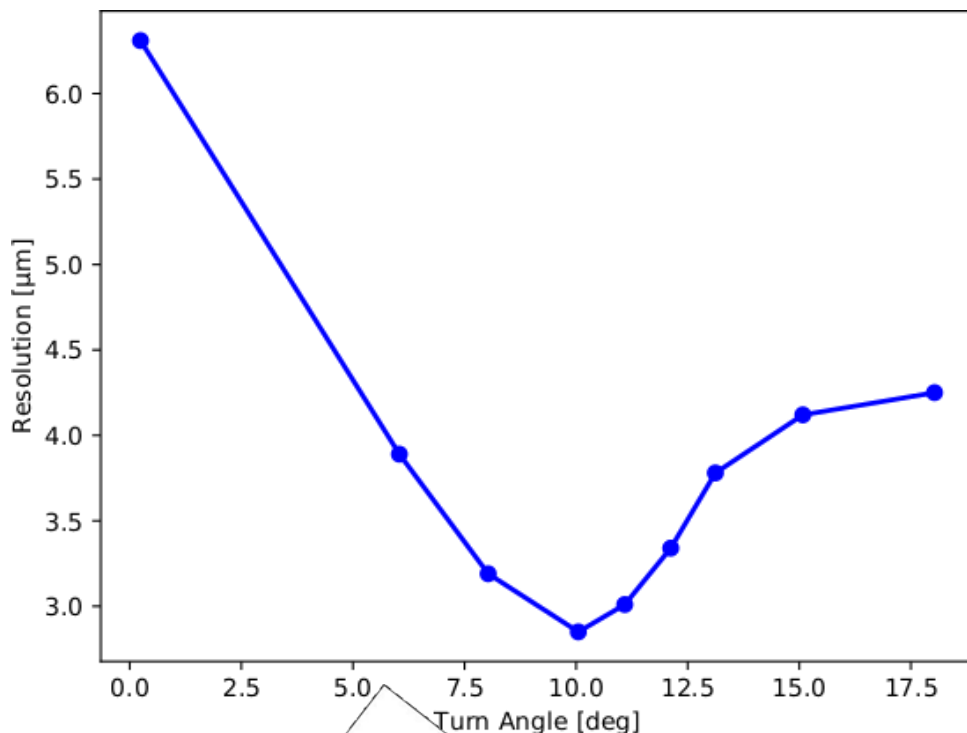
Cluster size = 2

$$V_{\text{bias}} = 30 \text{ V}$$

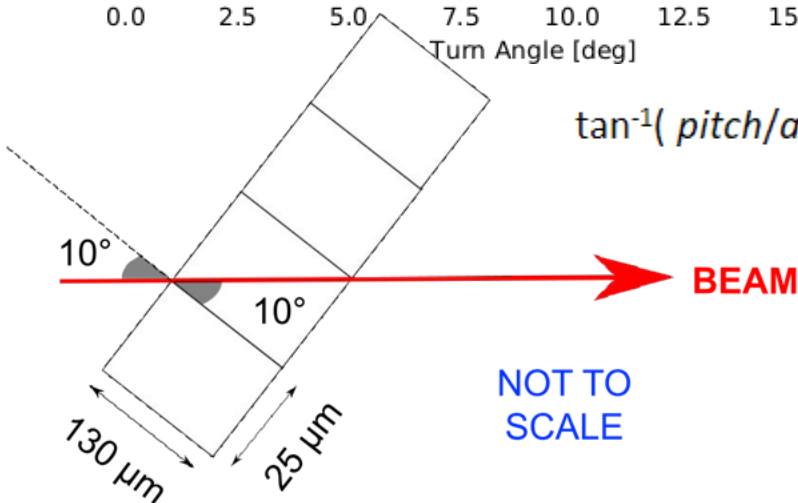
NOT TO SCALE



Resolution vs Turning angle: $25 \times 100 \mu\text{m}^2$



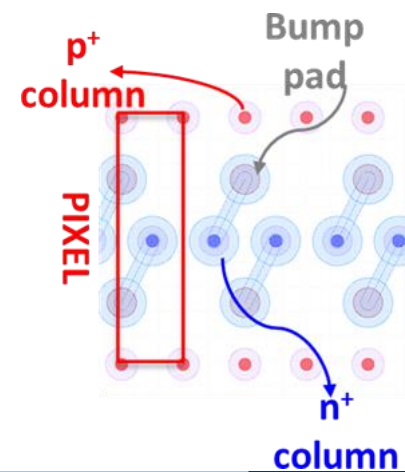
- Module rotated around short $25 \mu\text{m}$ pitch coordinate
- Best $\sigma_{\text{DUT}} \sim 3 \mu\text{m}$ @ $\sim 10^\circ$
- In most of the angular range σ_{DUT} is $4.5 \mu\text{m}$ or better
- First measurement for a 3D $25 \times 100 \mu\text{m}^2$ along $25 \mu\text{m}$ direction



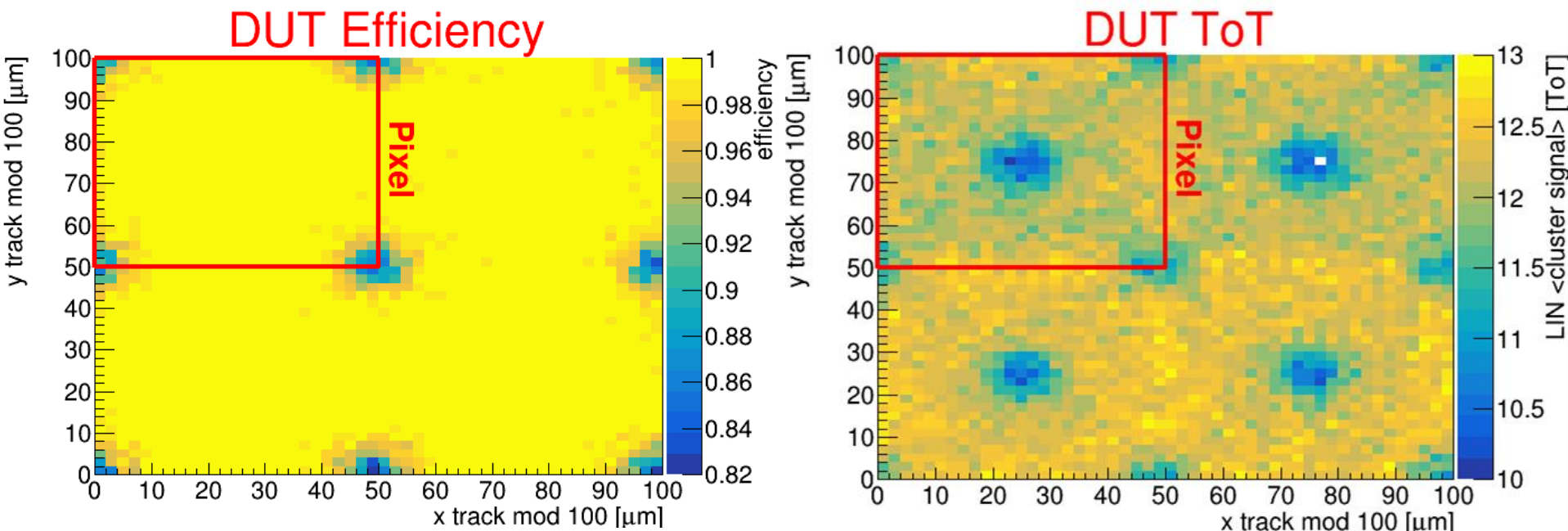
$$\tan^{-1}(\text{pitch}/\text{active_thickness}) = \tan^{-1}(25/130) \simeq 11^\circ$$

Cluster size = 2

$$V_{\text{bias}} = 30 \text{ V}$$

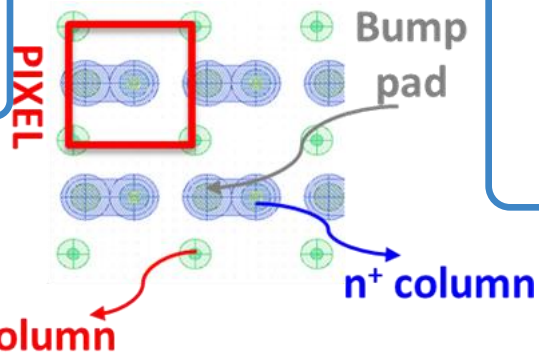


Hit efficiency and ToT: 50×50 μm² (MA)



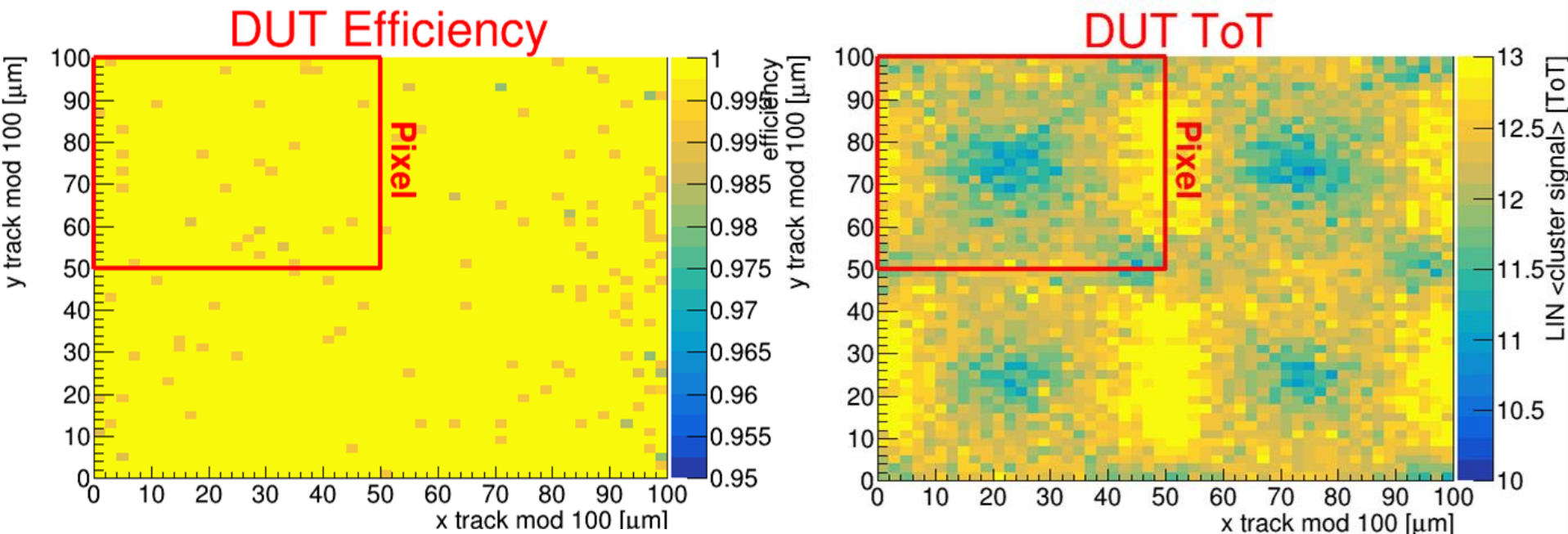
- Efficiency map for 2×2 pixel grid
- Efficiency drop near p⁺ columns
- High efficiency near n⁺ columns
- Global efficiency > 99%

$V_{\text{bias}} = 30 \text{ V}$
Orthogonal beam incidence

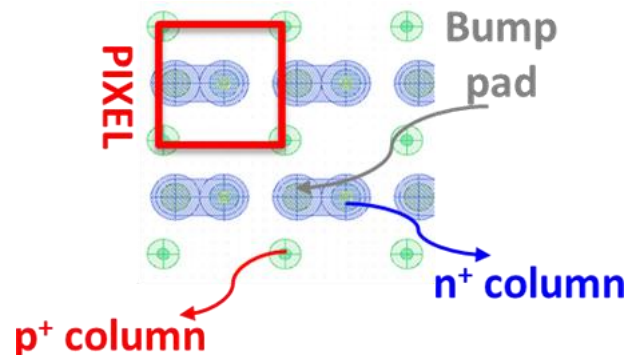


- Tot map for 2×2 pixel grid
- Low average Tot near n⁺ columns
 - Low collected charge (due to passive column), but high efficiency

Cluster size, ToT, Efficiency: $50 \times 50 \mu\text{m}^2$ (MA) @ 6°



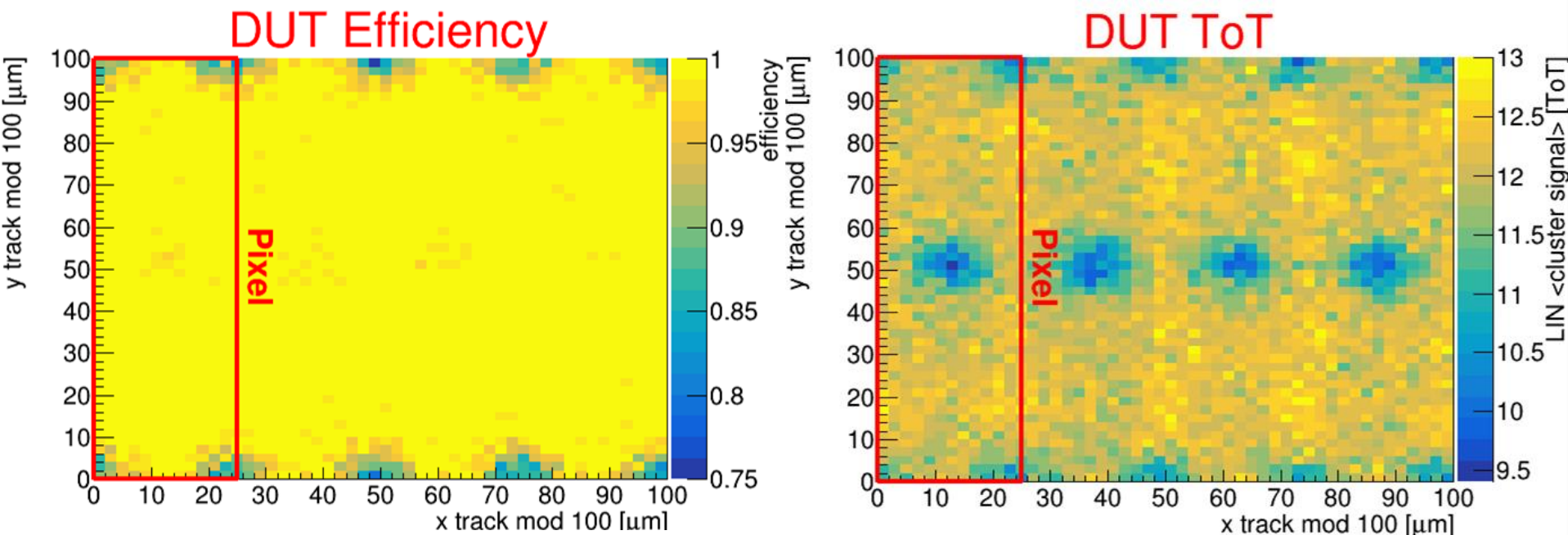
- Column inefficiencies are no longer there @ 6°
- Charge sharing due to rotation visible from ToT maps for 2×2 pixel grid



$$V_{\text{bias}} = 30 \text{ V}$$

Rotation of 6°

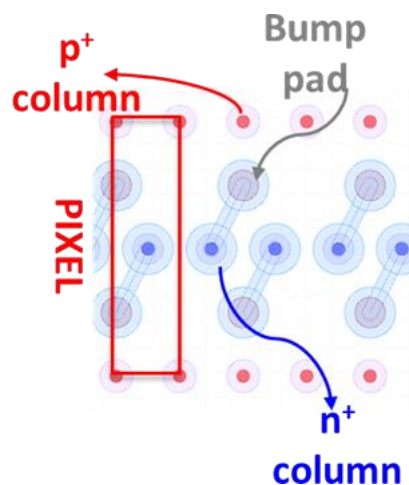
Hit efficiency and signal charge: $25 \times 100 \mu\text{m}^2$



- Efficiency map for 4×1 pixel grid
- Efficiency drop near p^+ columns
- High efficiency near n^+ columns
- Global efficiency $> 99\%$

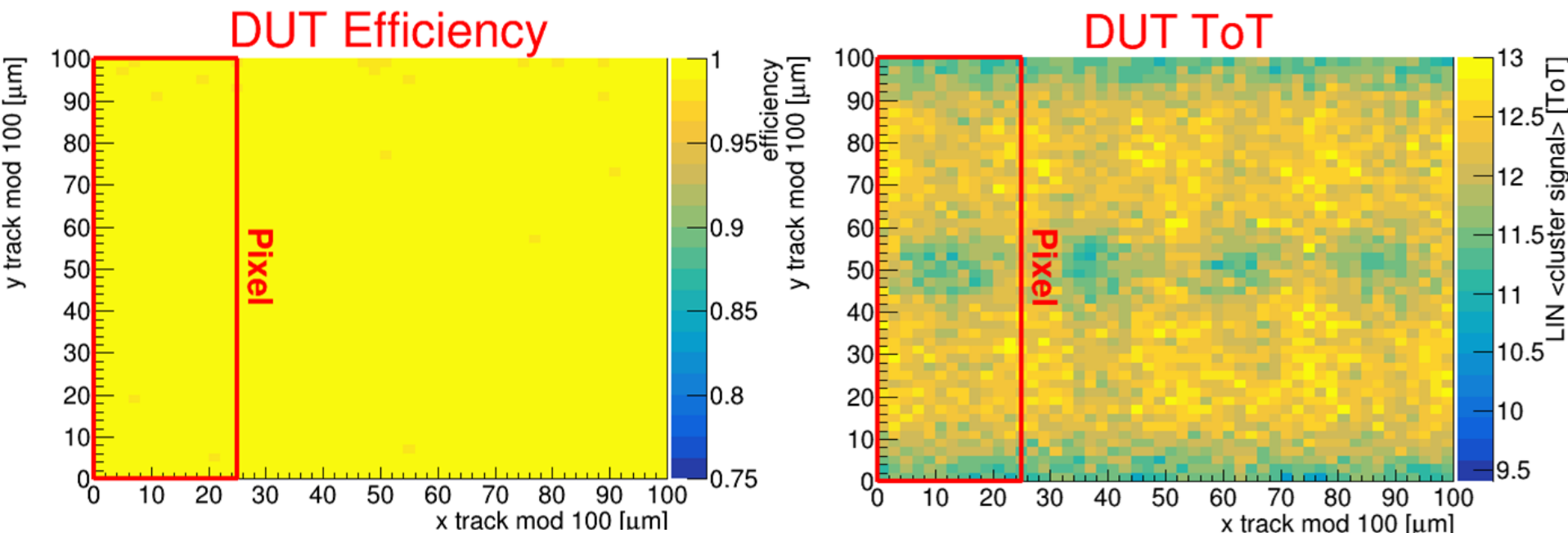
$$V_{\text{bias}} = 30 \text{ V}$$

Orthogonal beam incidence



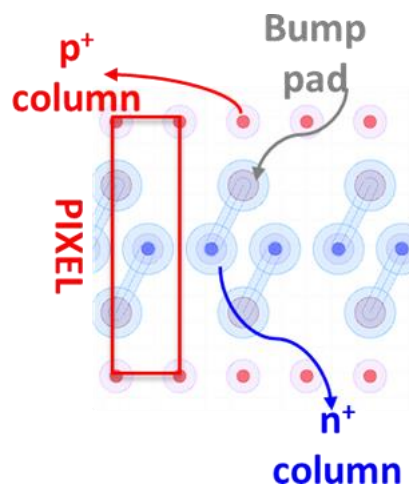
- Tot map for 4×1 pixel grid
- Low average Tot near n^+ columns
 - Low collected charge (due to passive column), but high efficiency

Cluster size, ToT, Efficiency: $25 \times 100 \mu\text{m}^2$ @ 5°



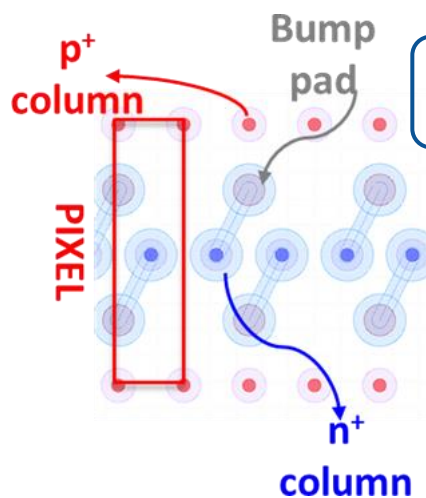
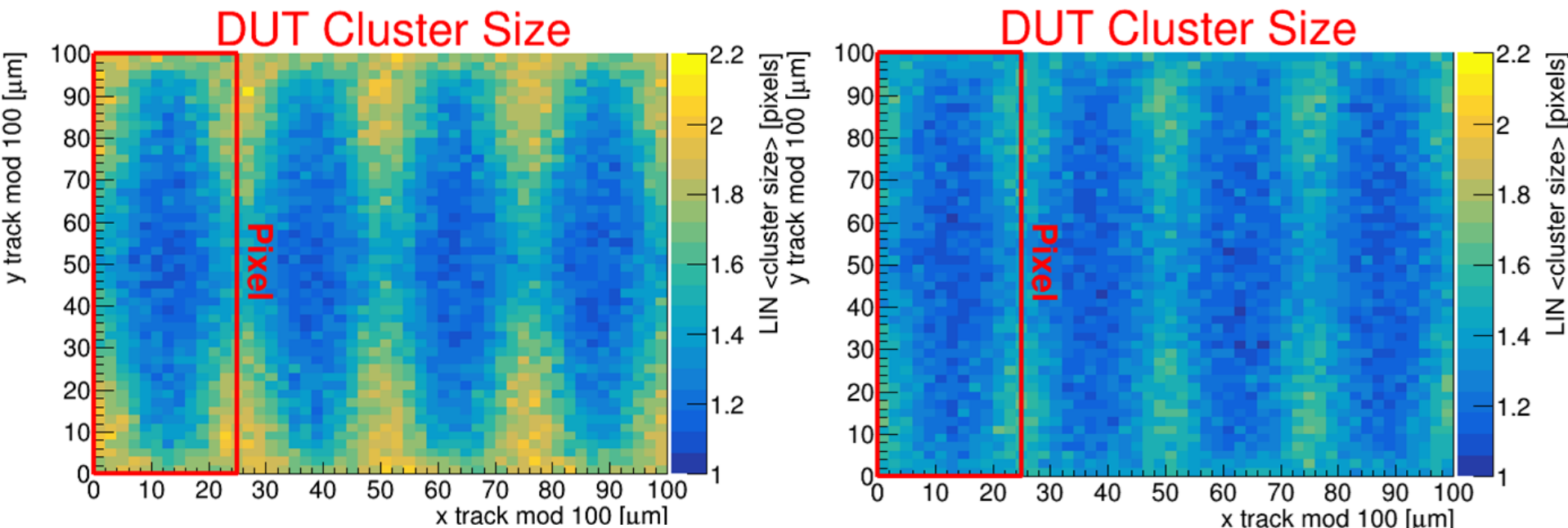
- Column inefficiencies are no longer there @ 5°

$V_{\text{bias}} = 30 \text{ V}$
Rotation of 5°



- Charge sharing due to rotation visible from ToT maps for 4×1 pixel grid

Cluster size: $25 \times 100 \mu\text{m}^2$



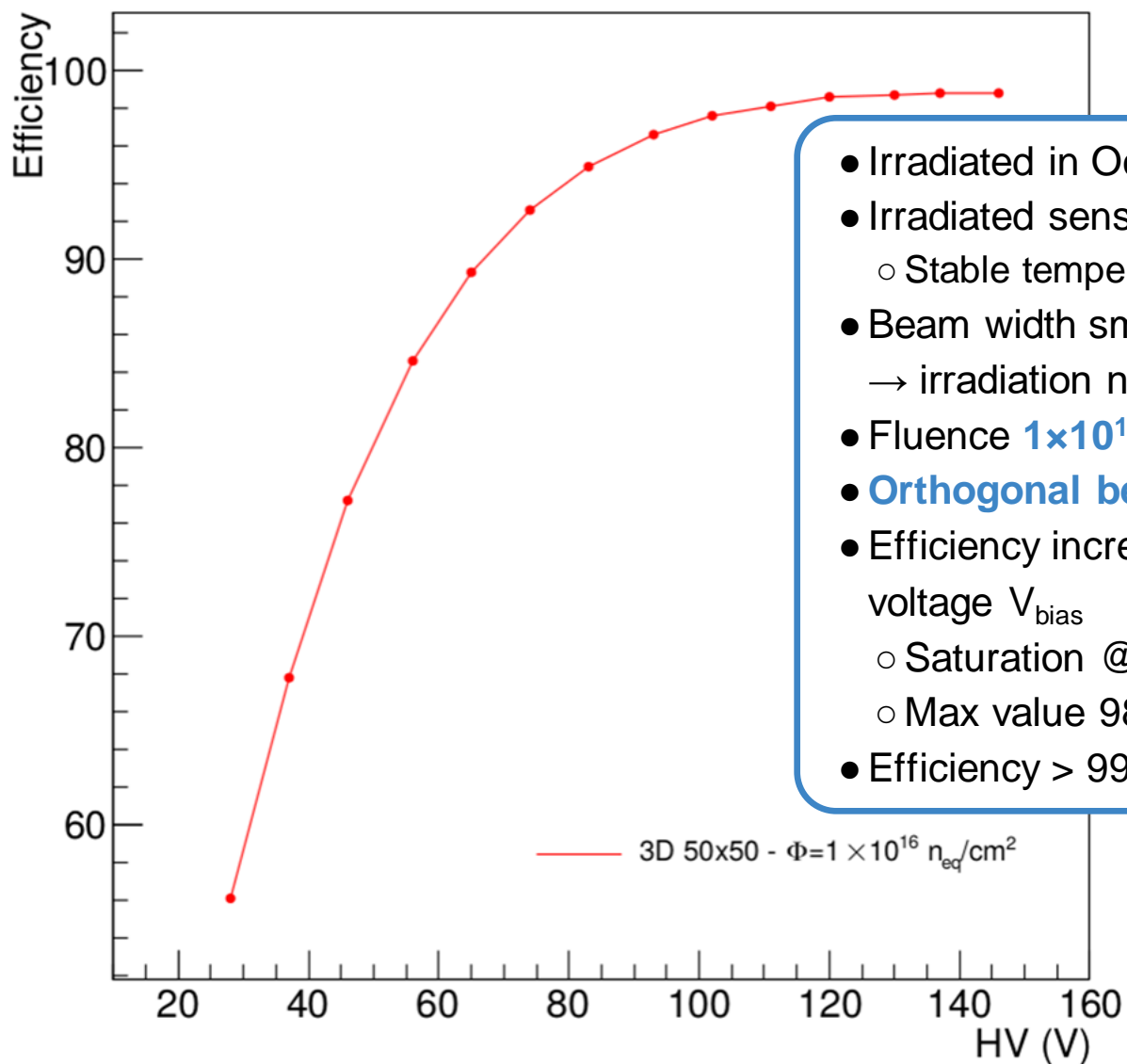
$V_{\text{bias}} = 6 \text{ V}$

Orthogonal beam incidence

$V_{\text{bias}} = 30 \text{ V}$

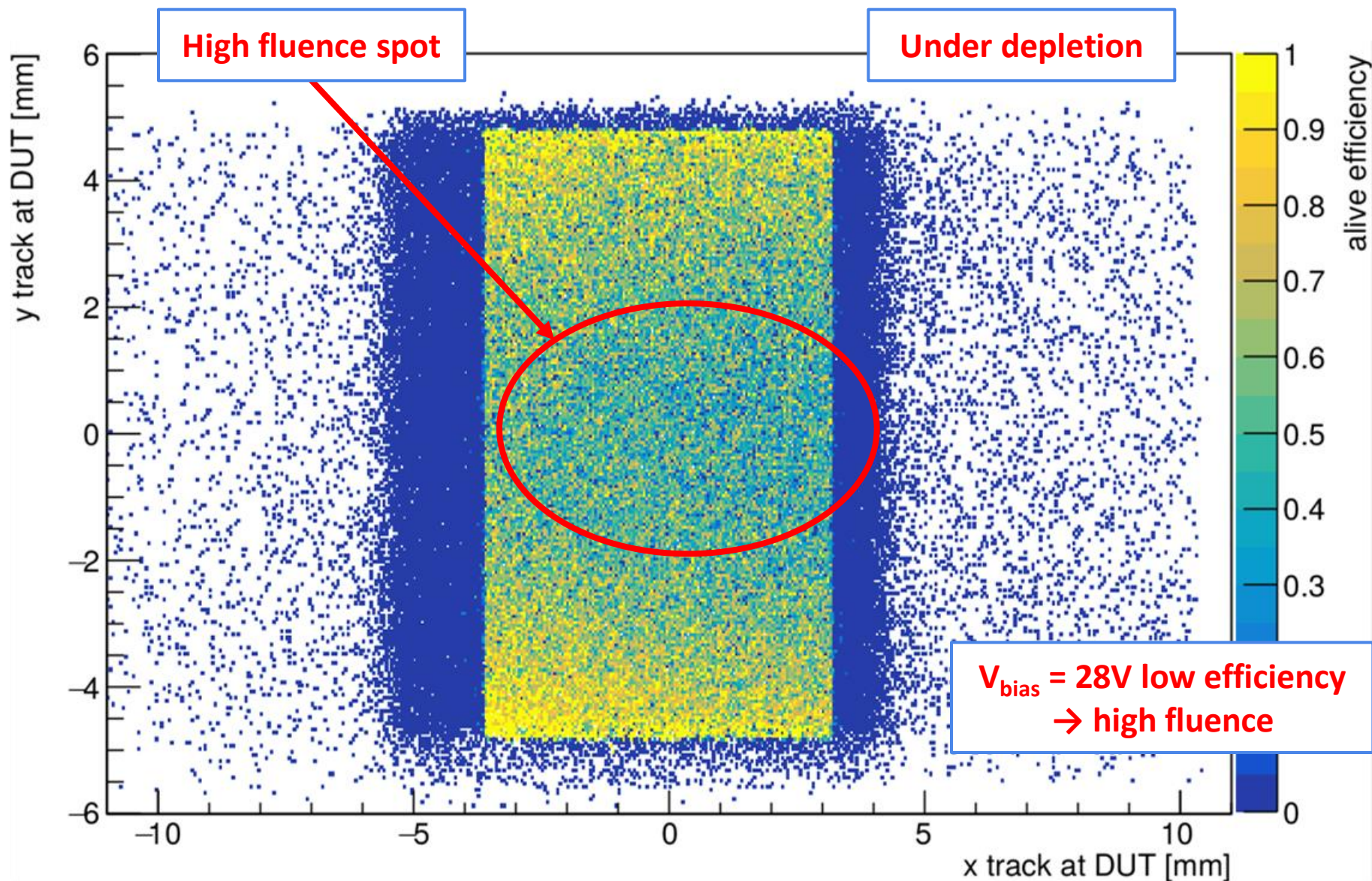
- Cluster size maps for 4×1 pixel grid
- Higher cluster size at lower bias voltage
 - More diffusion \rightarrow more charge sharing between pixels

Irradiated $50 \times 50 \mu\text{m}^2$: bias scan

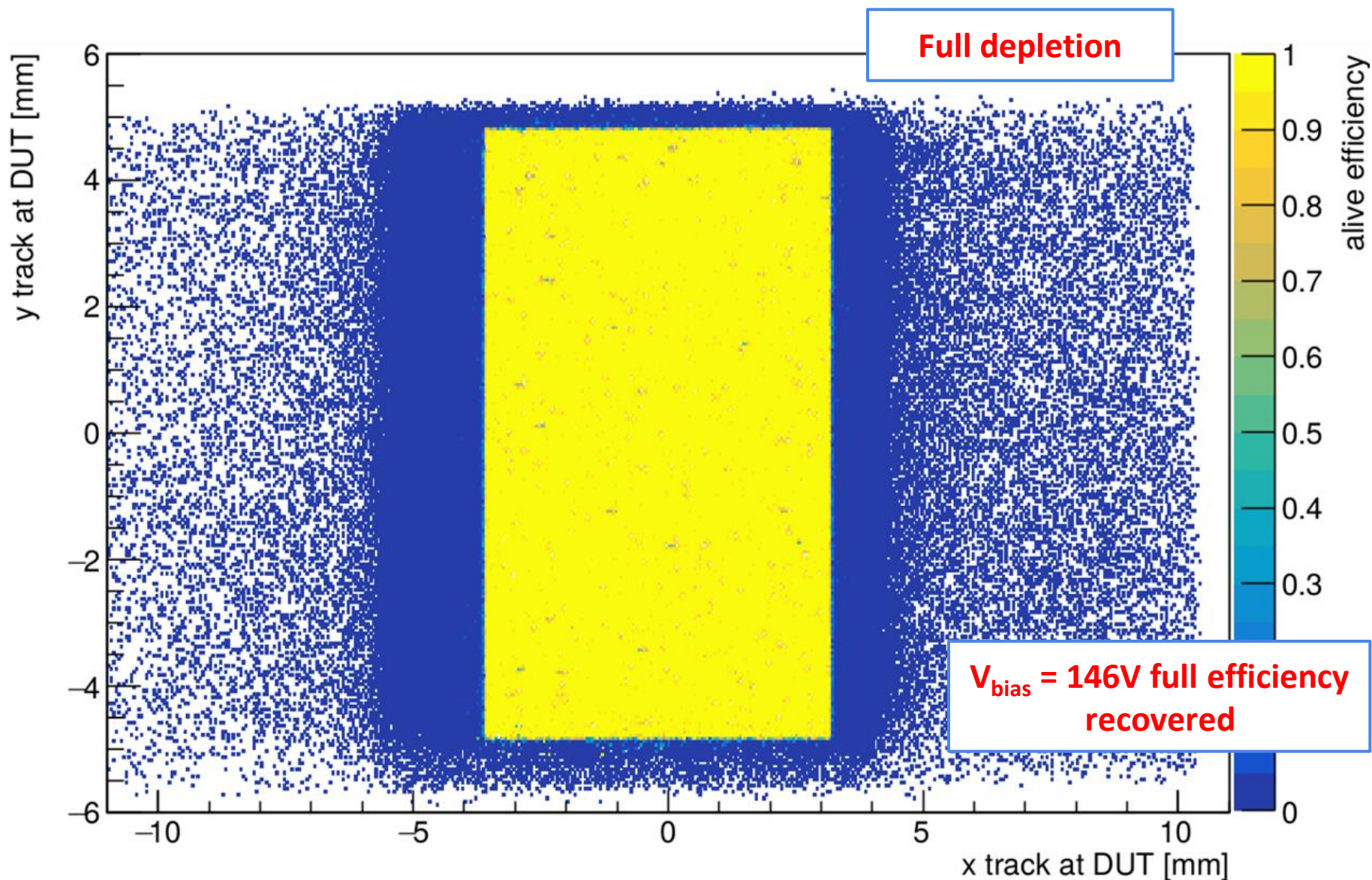


- Irradiated in Oct 2018 @ CERN
- Irradiated sensor kept inside a cooling box:
 - Stable temperature of -27°C
- Beam width smaller than chip
→ irradiation not uniform
- Fluence $1 \times 10^{16} n_{\text{eq}} \text{cm}^{-2}$, 6 MGy
- **Orthogonal beam incidence**
- Efficiency increases with effective bias voltage V_{bias}
 - Saturation @ $V_{\text{bias}} = 110\text{V}$
 - Max value 98.8% @ $V_{\text{bias}} = 146\text{V}$
- Efficiency > 99% with rotations > 6°

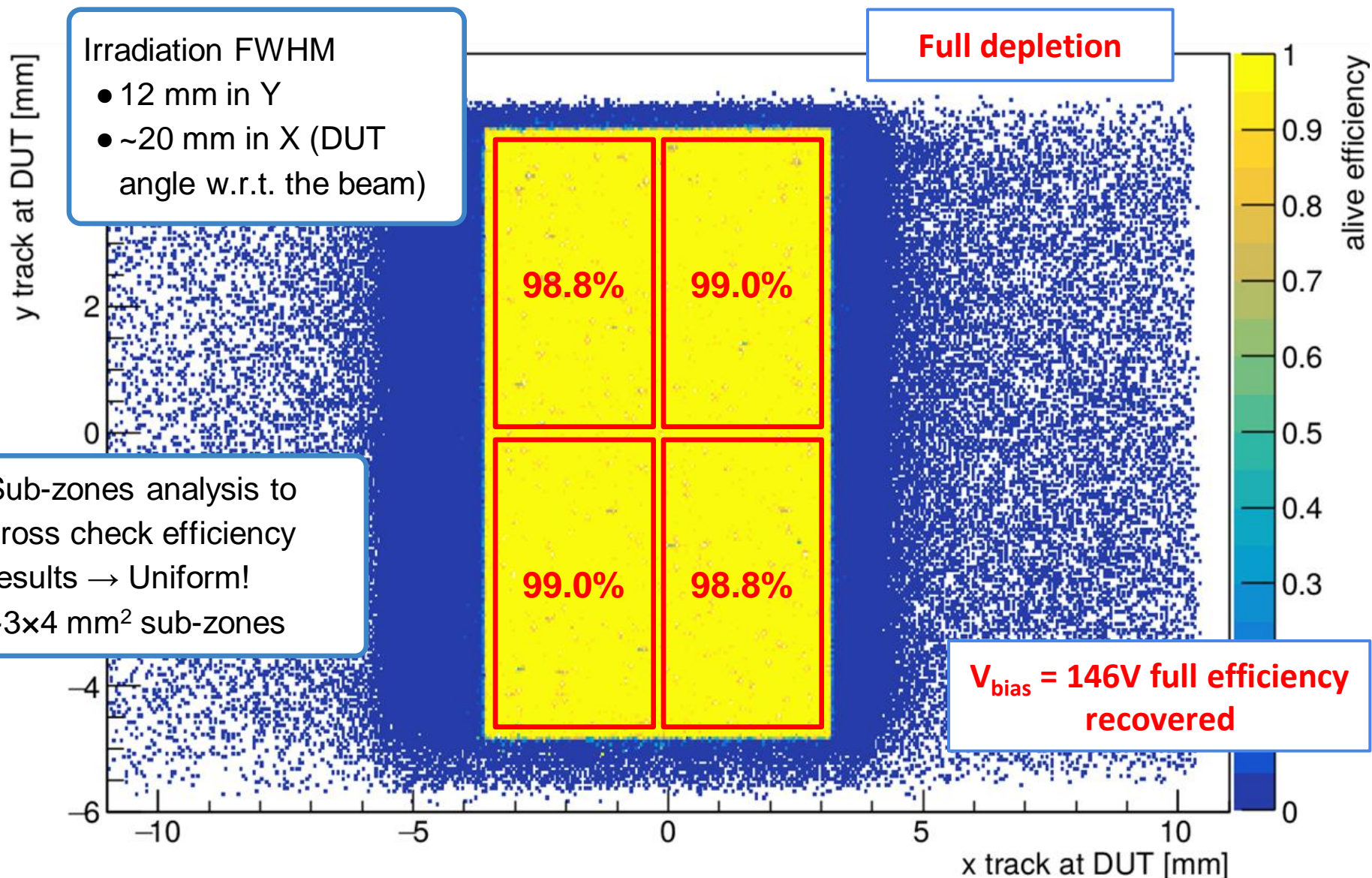
Irradiated $50 \times 50 \mu\text{m}^2$: hit efficiency studies



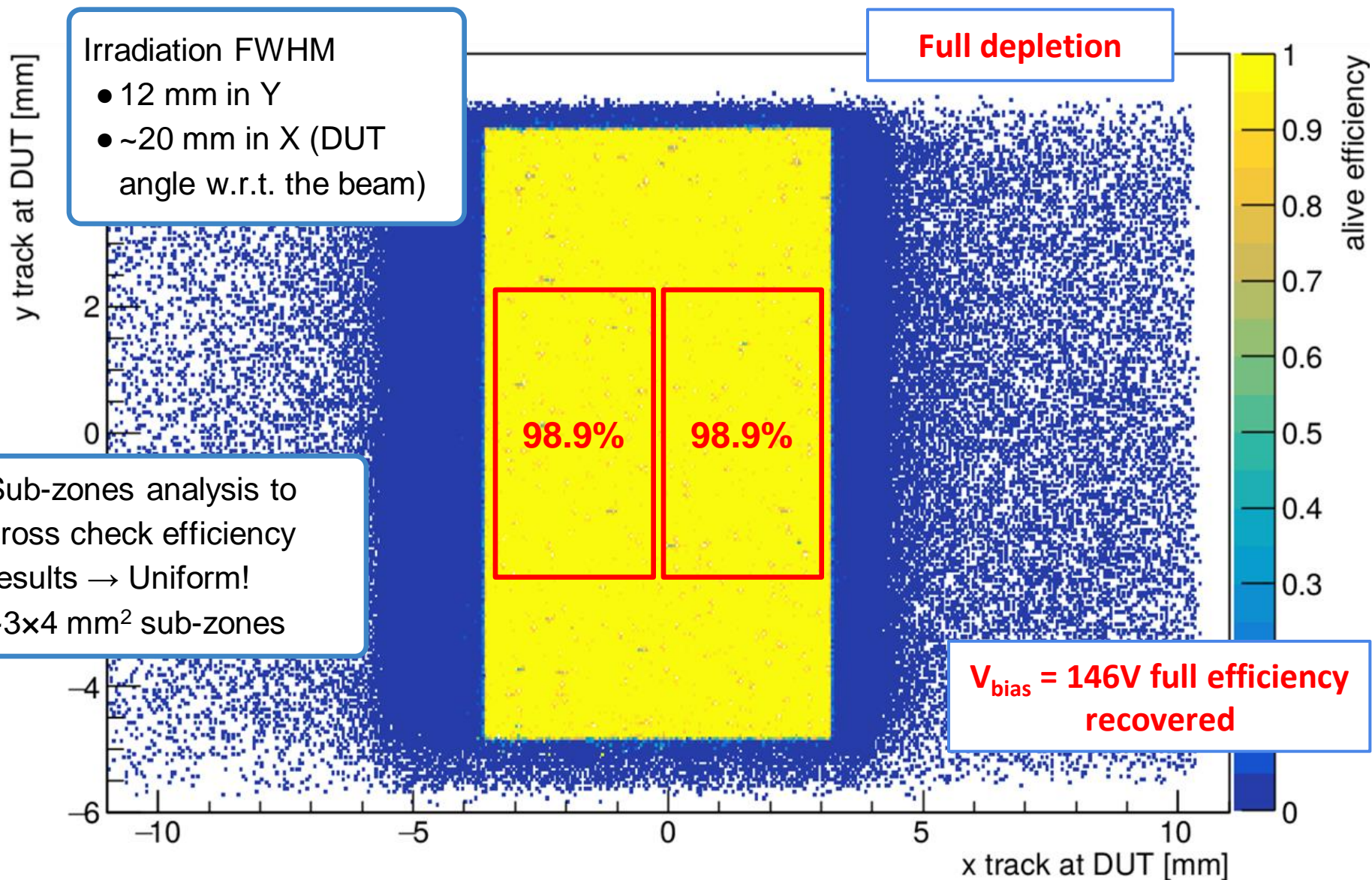
Irradiated $50 \times 50 \mu\text{m}^2$: hit efficiency studies



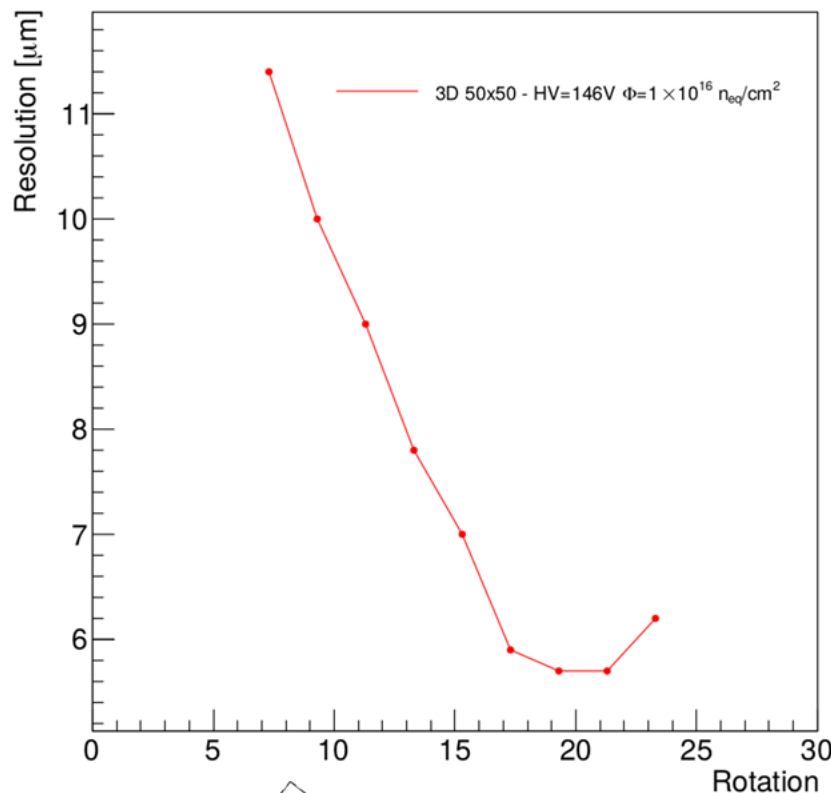
Irradiated $50 \times 50 \mu\text{m}^2$: hit efficiency studies



Irradiated $50 \times 50 \mu\text{m}^2$: hit efficiency studies



Irradiated 50×50 μm²: Resolution vs Turning angle



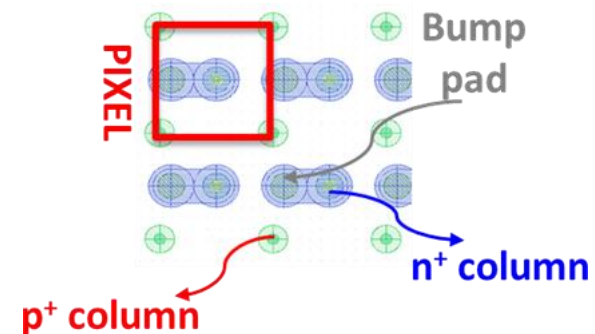
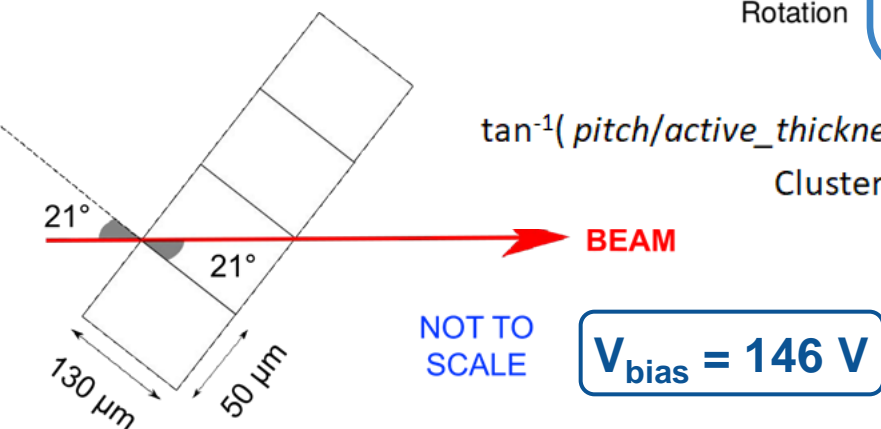
- Residuals fit (Student's t-distribution) on rotated (rot) and unrotated (no-rot) coordinates
- Using σ from fit, telescope resolution (res_{tele}) estimated with

$$res_{tele}^2 = \sigma_{no-rot}^2 - res_{trivial}^2, \text{ with } res_{trivial} = (50/\sqrt{12}) \mu\text{m}$$

- The resolution of the rotated coordinate (res_{rot}) has been estimated with (conservative):

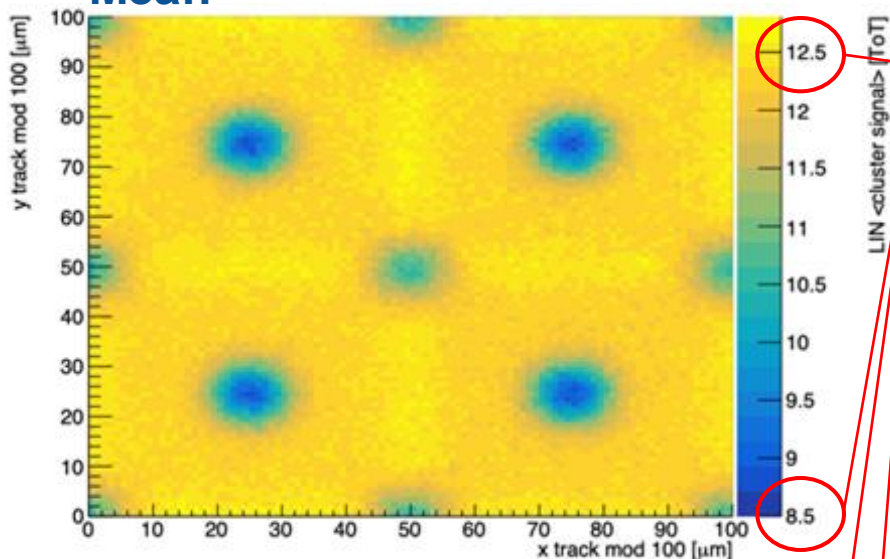
$$res_{rot}^2 = \sigma_{rot}^2 - res_{tele}^2$$

- Irradiated 3D sensor resolution is 5.7 μm at about 20° turn angle



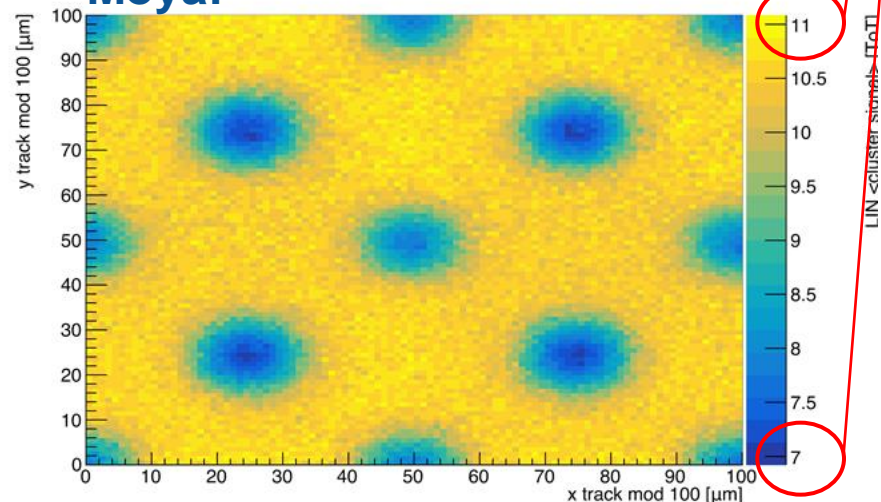
Fresh 50×50 μm^2 : recent studies on ToT estimation

Mean



Different scales, but same range “shifted”. Takes into account the different “mean value” of the plot

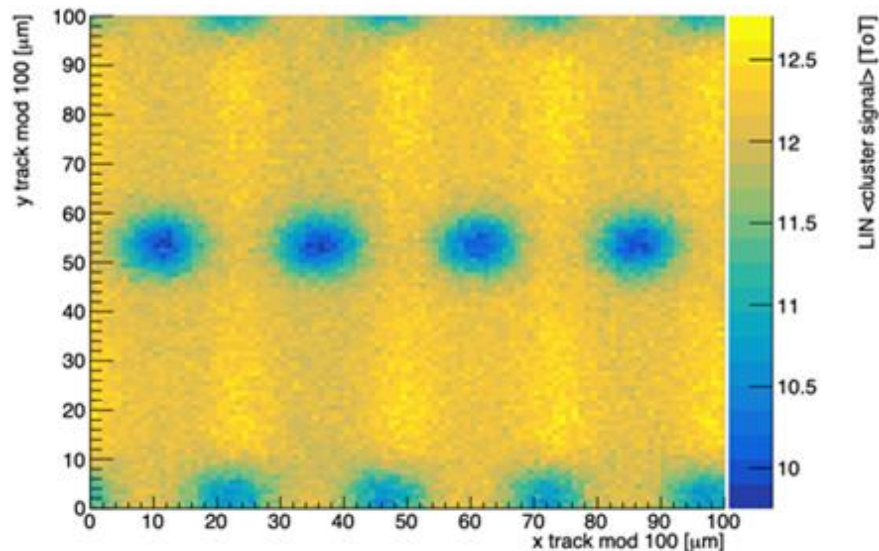
Moyal



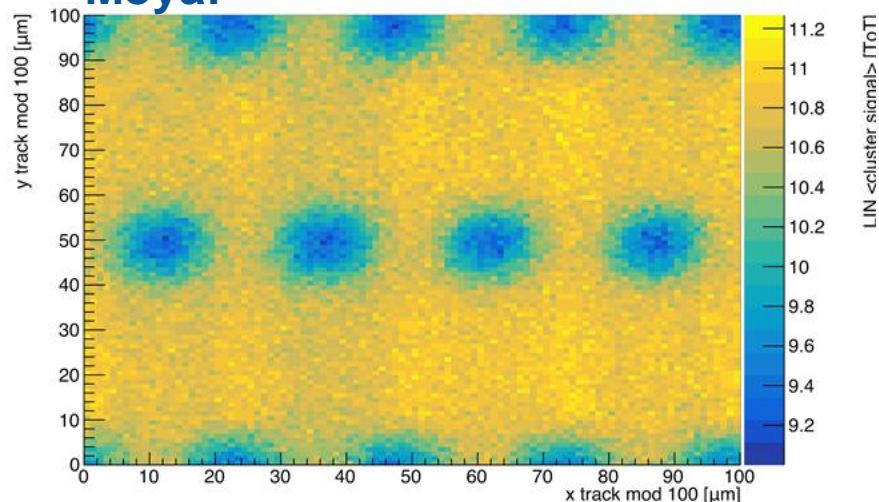
- High statistics plot with 100×100 bins, low statistics with 50×50 bins, contributions from the whole sensor moduled 100 μm (2×2 pixels for 50×50 μm^2 pitch)
- Mean value of ToT inside the bins tend to over-estimate the MPV and is sensible to cut_off
- Moyal distribution, on the other hand, needs post processing → different possible approaches studied
- All the methods give very similar and reliable results

Fresh 25×100 μm^2 : recent studies on ToT estimation

Mean



Moyal



- High statistics plot with 100×100 bins, low statistics with 50×50 bins, contributions from the whole sensor moduled 100 μm (2×2 pixels for 50×50 μm^2 pitch)
- Mean value of ToT inside the bins tend to over-estimate the MPV and is sensible to cut_off
- Moyal distribution, on the other hand, needs post processing → different possible approaches studied
- All the methods give very similar and reliable results

Conclusions

- CMS Inner Tracker Upgrade is extremely challenging
- Good results with fresh FBK 3D modules, both $50 \times 50 \mu\text{m}^2$ and $25 \times 100 \mu\text{m}^2$:
 - ✓ Fully efficient ($>99\%$) at 6 V of bias voltage for perpendicular tracks
 - ✓ Resolution up to $\sim 5(3) \mu\text{m}$ for 50×50 (25×100) μm^2
- Irradiated ($1 \times 10^{16} n_{\text{eq}} \text{cm}^{-2}$) FBK 3D module is also very good in performances:
 - ✓ Fully efficient at ~ 100 V
 - ✓ Resolution up to $\sim 5.7 \mu\text{m}$ for $50 \times 50 \mu\text{m}^2$
 - ✓ 98.8% hit efficiency
- 3D pixels are confirmed to be strong candidates for the inner layers of the silicon trackers to be built for the HL-LHC

Thank you for your attention



Thank you for your attention

Many thanks to:

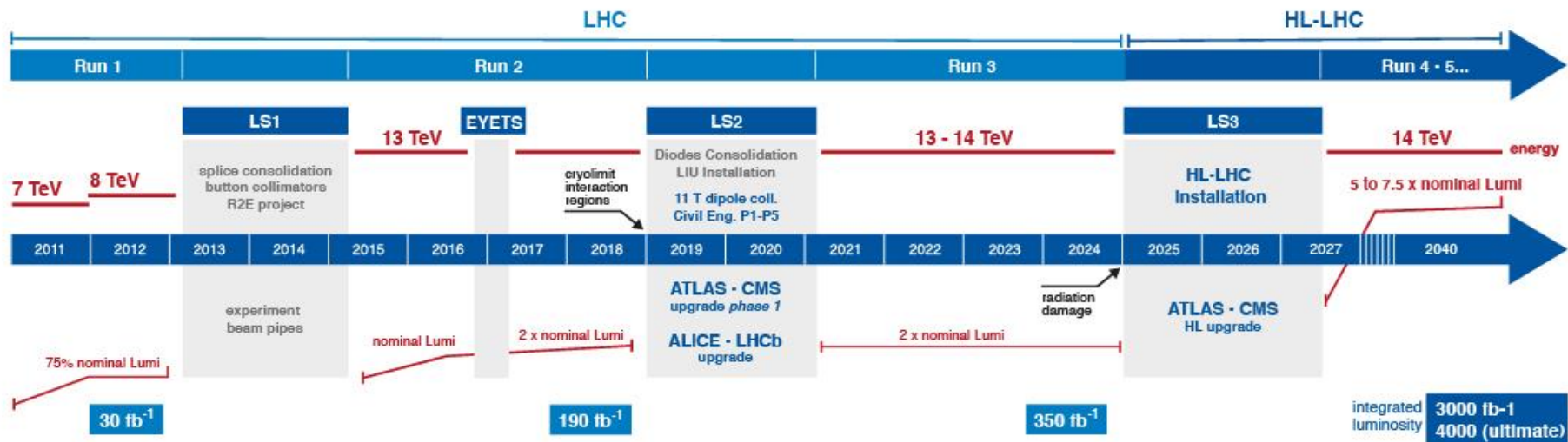
M. Meschini, R. Ceccarelli, S. Gennai, A. Cassese, M. Boscardin, E. Curras, L. Demaria, M. Dinardo, J. Duarte, A. Ebrahimi, G. F. Dalla Betta, M. Fernandez, F. Ficorella, L. Gaioni, A. Garcia, C. Gemme, S. Gennai, G. Gomez, J. Gonzalez, R. Mendicino, A. Messineo, E. Monteil, L. Moroni, S. Parolia, D. Pitzl, S. Ronchin, G. Sguazzoni, E. Silva, J. Sonneveld, G. Steinbrück, I. Vila, L. Viliani, D. Zuolo

Backup

CMS Phase-2 tracker @ HL-LHC



LHC / HL-LHC Plan



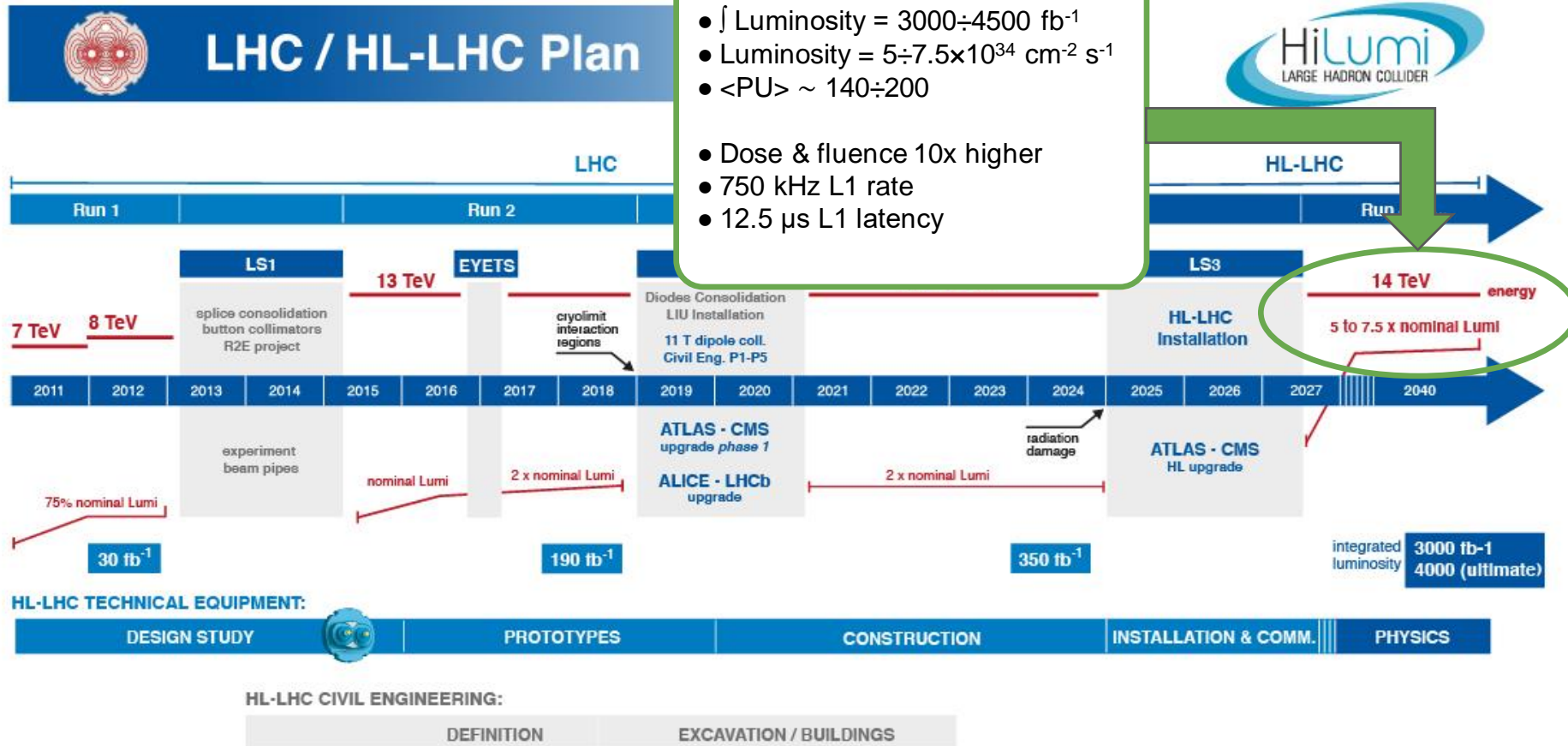
HL-LHC TECHNICAL EQUIPMENT:



HL-LHC CIVIL ENGINEERING:



CMS Phase-2 tracker @ HL-LHC

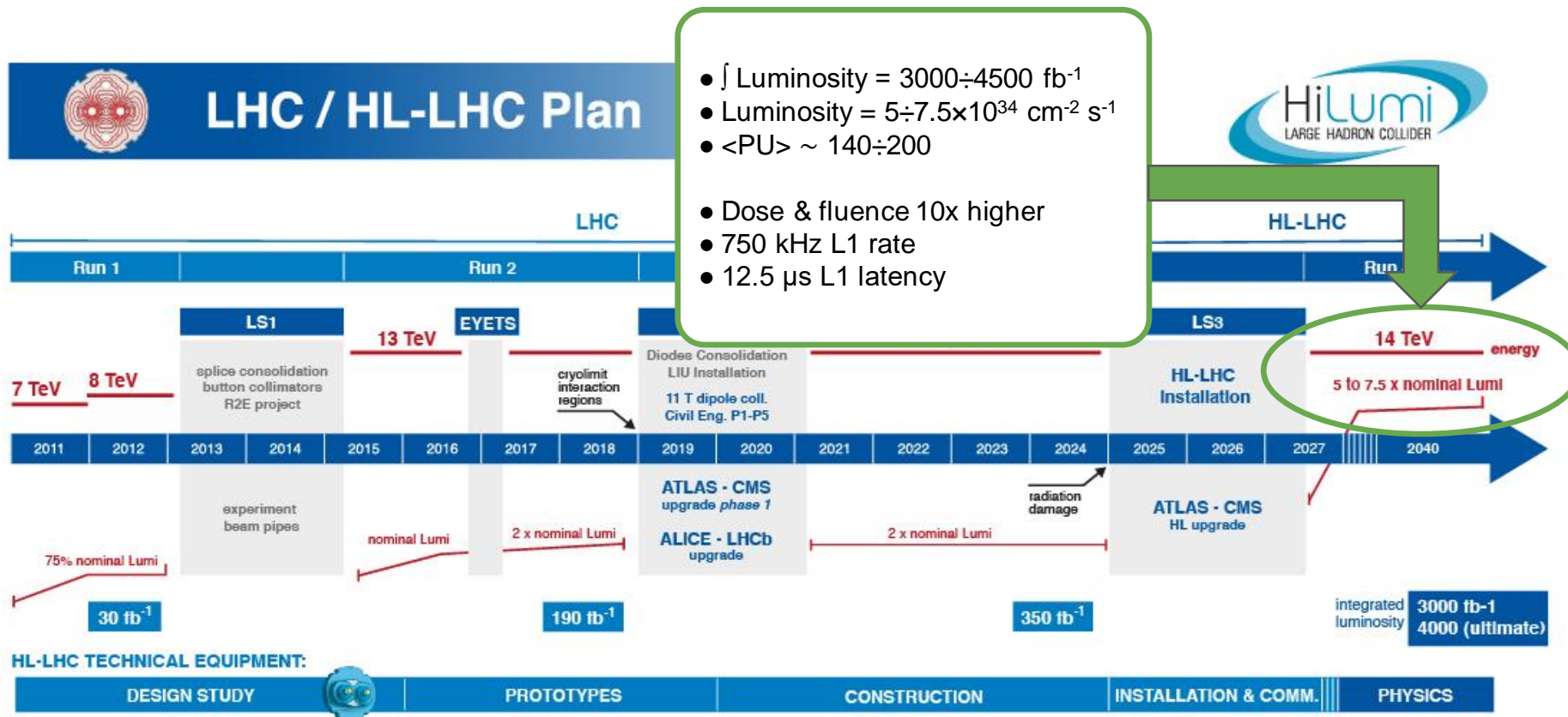


- \int Luminosity = 3000÷4500 fb⁻¹
- Luminosity = 5÷7.5×10³⁴ cm⁻² s⁻¹
- <PU> ~ 140÷200
- Dose & fluence 10x higher
- 750 kHz L1 rate
- 12.5 μs L1 latency



14 TeV energy
5 to 7.5 x nominal Lumi

CMS Phase-2 tracker @ HL-LHC

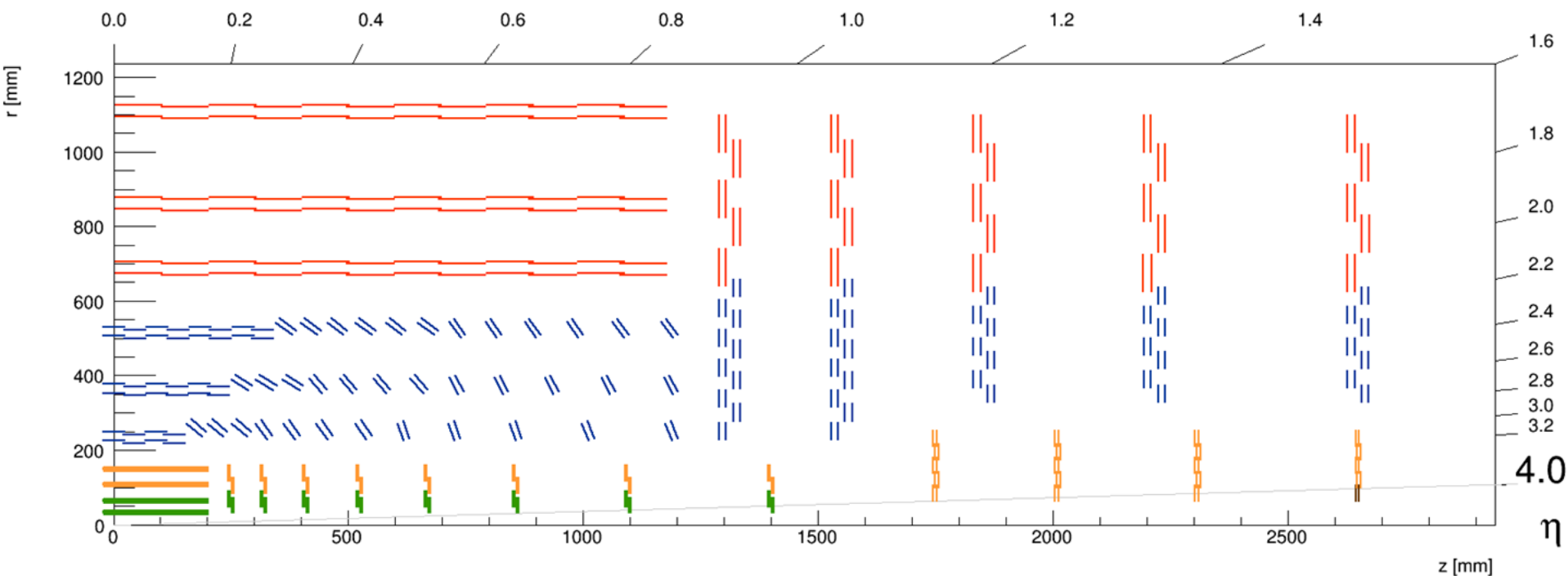


- \int Luminosity = 3000÷4500 fb⁻¹
- Luminosity = 5÷7.5×10³⁴ cm⁻² s⁻¹
- \langle PU \rangle ~ 140÷200

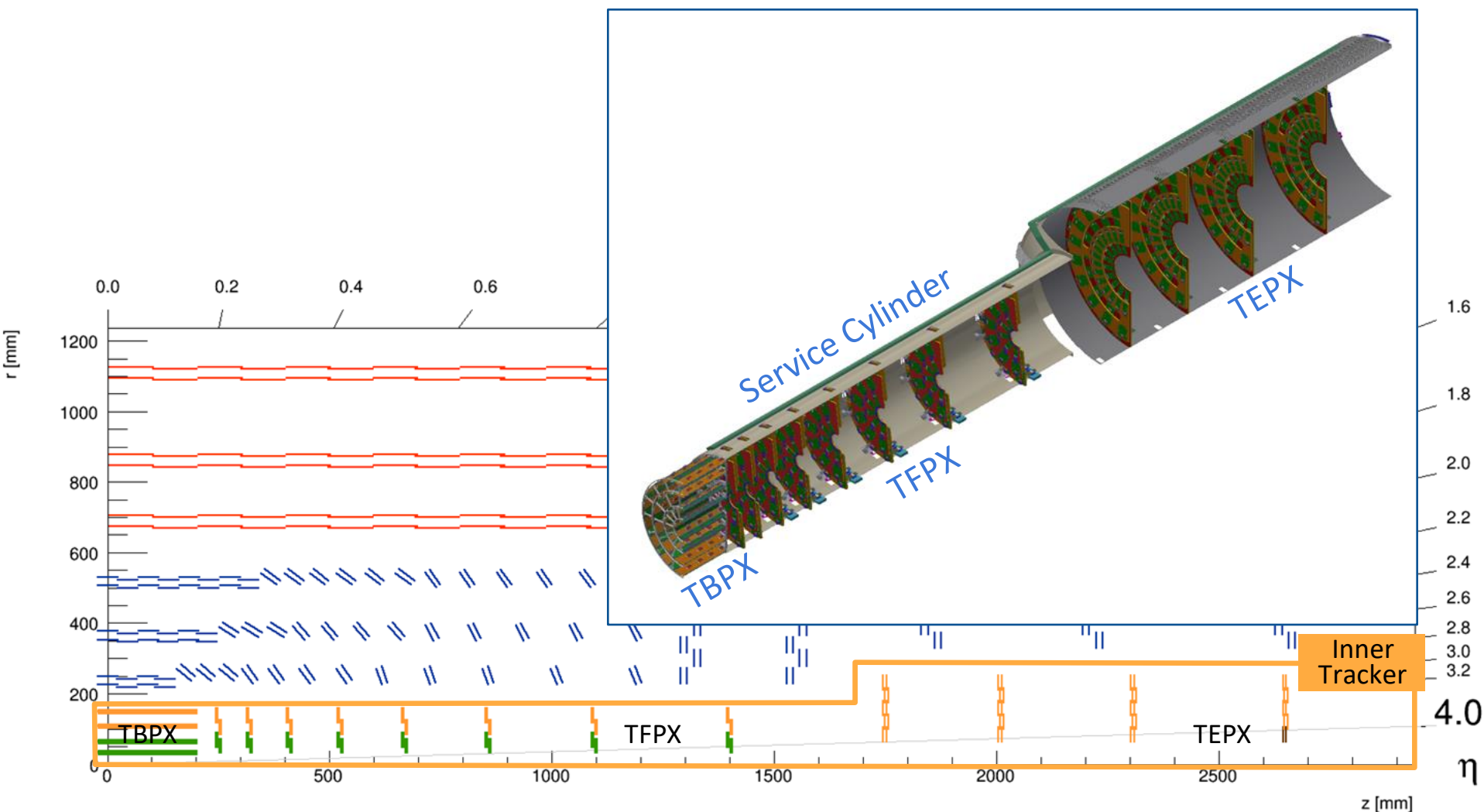
- Dose & fluence 10x higher
- 750 kHz L1 rate
- 12.5 μ s L1 latency

The present CMS tracker cannot sustain the foreseen radiation levels and data rates and has to be completely replaced

Inner Tracker upgrade for High Luminosity



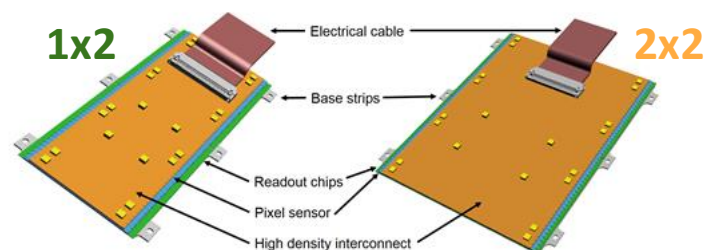
Inner Tracker upgrade for High Luminosity



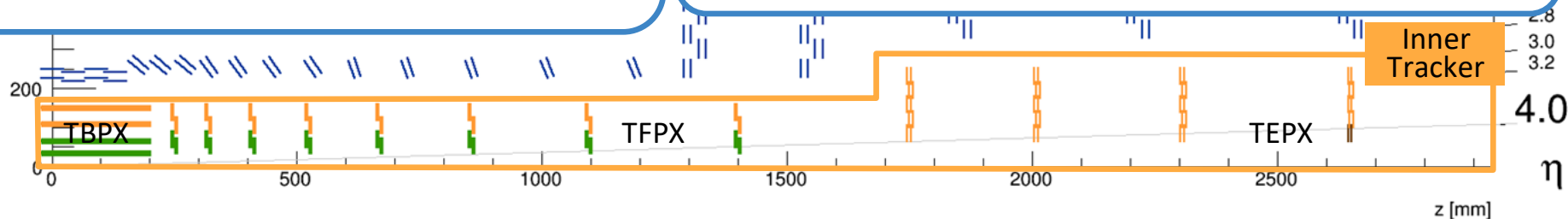
Inner Tracker upgrade for High Luminosity

Main requests and innovations

- **High radiation tolerance:**
 - 2.3×10^{16} n_{eq}/cm^2 , fluence
 - 1.2 Grad, TID
- **Improve tracks separation:**
 - High granularity
 - High bandwidth (up to 3.5 GHz/cm² occupancy)
 - Low material budget
- **Extend tracking coverage:**
 - $|\eta| \leq 4$
- **Stringent space constraints**



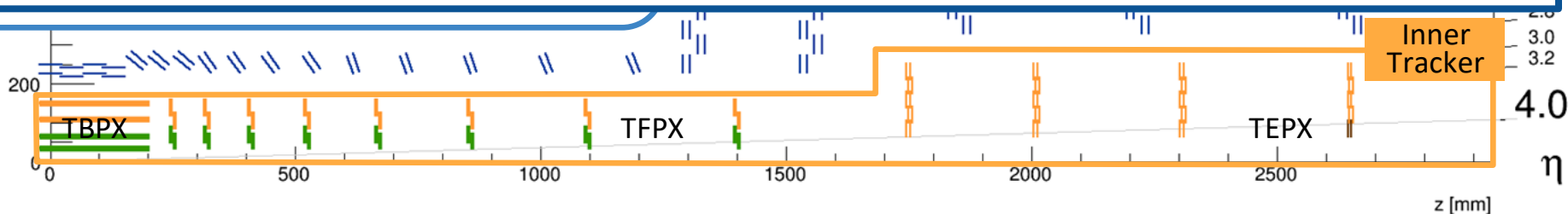
- TBPX 4 layers, TFPX 2x8 disks, TEPX 2x4 disks
- **3900 modules**
- **2×10^9 pixels** (124×10^6 in Phase-1)
- 4.9 m²
- Hybrid modules with **2 (1x2)** or **4 (2x2)** readout chips
- **1156 modules, 2736 modules**
- Simple mechanics:
 - Can be removed for maintenance
 - Barrel splits in half at $z \sim 0$
 - Disks with planar geometry



Inner Tracker upgrade for High Luminosity

A lot of talks on HL-LHC CMS Inner Tracker (and not only):

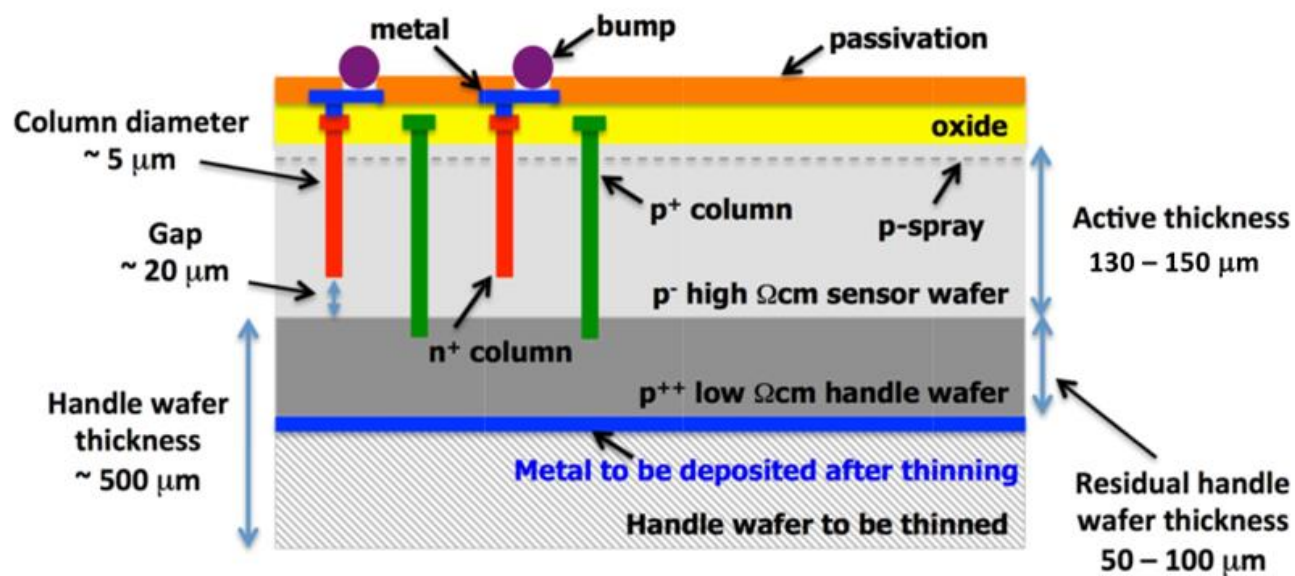
- Jory Sonneveld talk (17th Feb 2020, 12:55): “The CMS Pixel Detector for the High Luminosity LHC” <https://indico.cern.ch/event/813597/contributions/3727821/>
- Corrinne Mills talk (17th Feb 2020, 15:15): “Performance of highly irradiated pixel sensors for the CMS HL-LHC upgrade” <https://indico.cern.ch/event/813597/contributions/3727828/>
- Finn Feindt talk (17th Feb 2020, 15:55): “Test Beam Characterization of Planar Pixel Sensors for the CMS Phase 2 Upgrade” <https://indico.cern.ch/event/813597/contributions/3727834/>
- Jordi Duarte Campderros talk (19th Feb 2020, 10:00): “Study of 3D pixel sensors after non-uniform proton irradiation” <https://indico.cern.ch/event/813597/contributions/3727824/>
- Roberto Seidita talk (19th Feb 2020, 16:00): “Serial powering at CMS silicon tracker detector for High Luminosity Upgrade” <https://indico.cern.ch/event/813597/contributions/3727820/>





3D Pixel Sensors R&D

- 3D sensors at FBK Foundry (Trento, Italy): a common R&D program with FBK shared between Italian researchers of CMS and ATLAS and funded by INFN (Italy)
- 6" Si-Si DWB (Direct Wafer Bonding). Active Device Float Zone, P type, resistivity $>3\text{k}\Omega\text{cm}$, $130\mu\text{m}$ (or $150\mu\text{m}$) thick. CZ Handle wafer, $0.1\text{-}1\ \Omega\text{cm}$ resistivity, $500\mu\text{m}$ thick.
- FBK Fully Top-side process: DRIE (Deep Reactive Ion Etching) technique
- Most of the sensors shown in this talk have been thinned down to a total thickness of $200\mu\text{m}$; the thickness foreseen for HL-LHC CMS Inner Tracker is $250\text{-}275\mu\text{m}$



RD53: the inner tracker readout chip

RD53 ROC

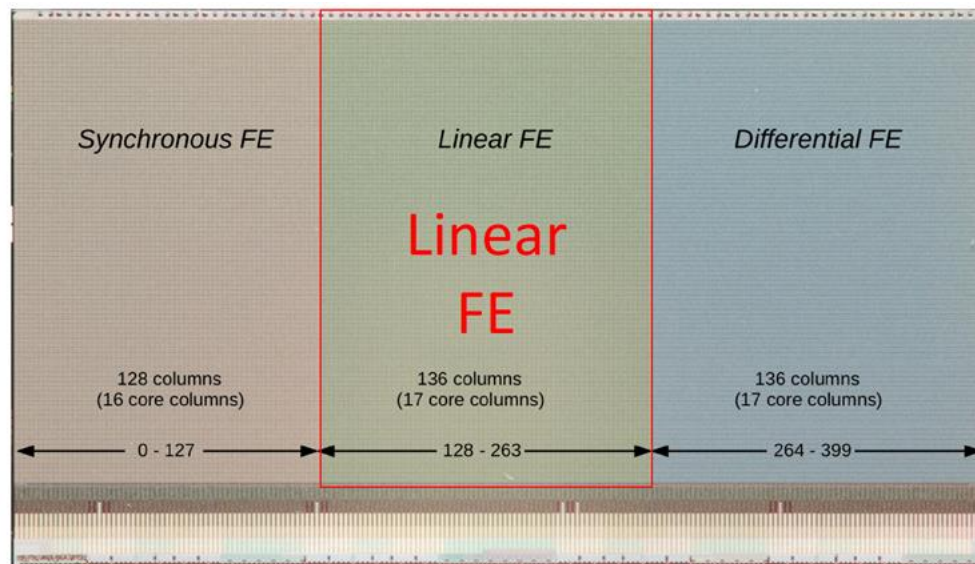
RD53 collaboration is developing an ROC with:

- Dead time $\leq 1\%$ @3.2 GHz/cm²
- 0.5 (possibly 1) Grad TID resistant
- 65 nm technology
- 50×50 μm^2 cell
- low threshold ($\leq 1000 e^-$)
- High hit and trigger rate (up to 4×1.28 Gb/s output links)
- Serial powering capabilities
- CMS chip size (16.8×21.6 mm², 336×432 cells)

RD53: the inner tracker readout chip

RD53A first prototype

- ½ total size ($50 \times 50 \mu\text{m}^2$ cell, 65 nm technology)
- Used for R&D
- Radiation hard up to 0.5 Grad
- Low threshold and high hit and rate capabilities (160 Mbps input and 1.28 Gbps output links)
- 3 analog Front-Ends (Synchronous, Linear, Differential)
- Time over Threshold counter to measure charge (4 bits); caveat ToT as charge unit
- CMS choice: Linear F.E.
- **All results presented here obtained using Linear F.E. (central section)**



RD53 ROC

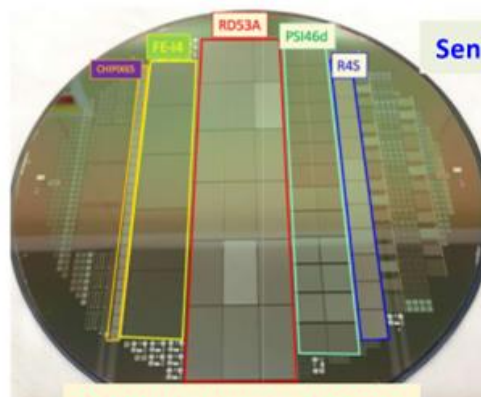
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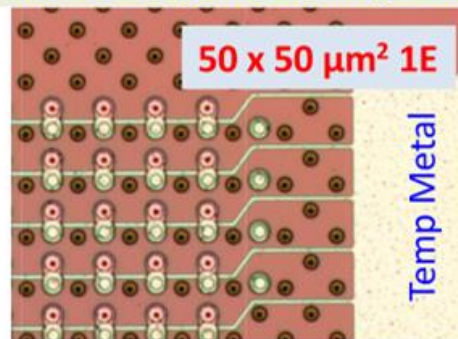
FBK 3D Pixel Batches: Mask Aligner and Stepper processes

“RD53A type” Sensors have $50 \times 50 \mu\text{m}^2$ or $25 \times 100 \mu\text{m}^2$ unit pixel cell size

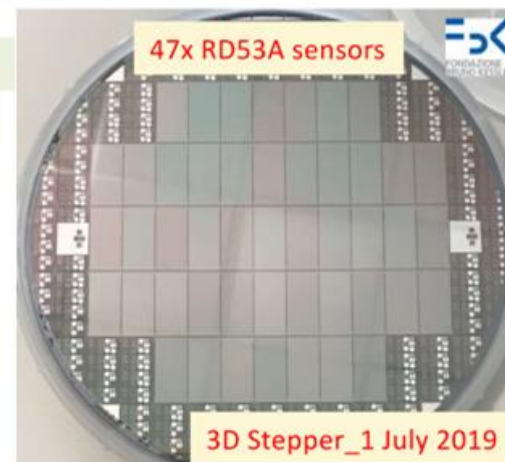


3D Mask Aligner Oct 2017
18x RD53A sensors

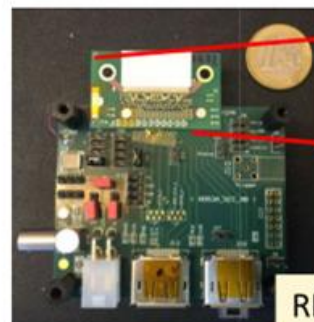
Sensor corner with guard columns (photo)



I-V curves done with Temporary Metal at FBK on all sensors

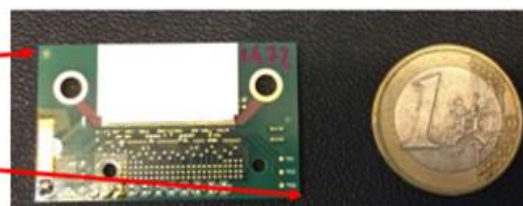


Readout Cards



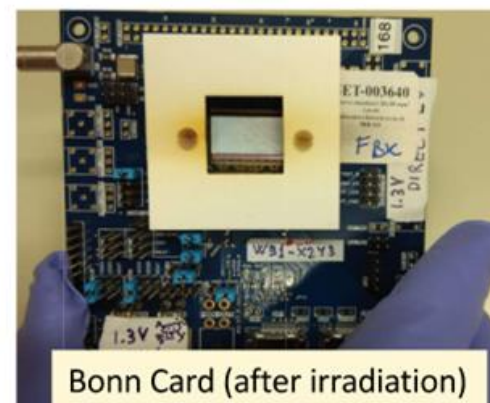
RICE adapter card

HSTD12 Hiroshima



RICE irradiation card (before irradiation)

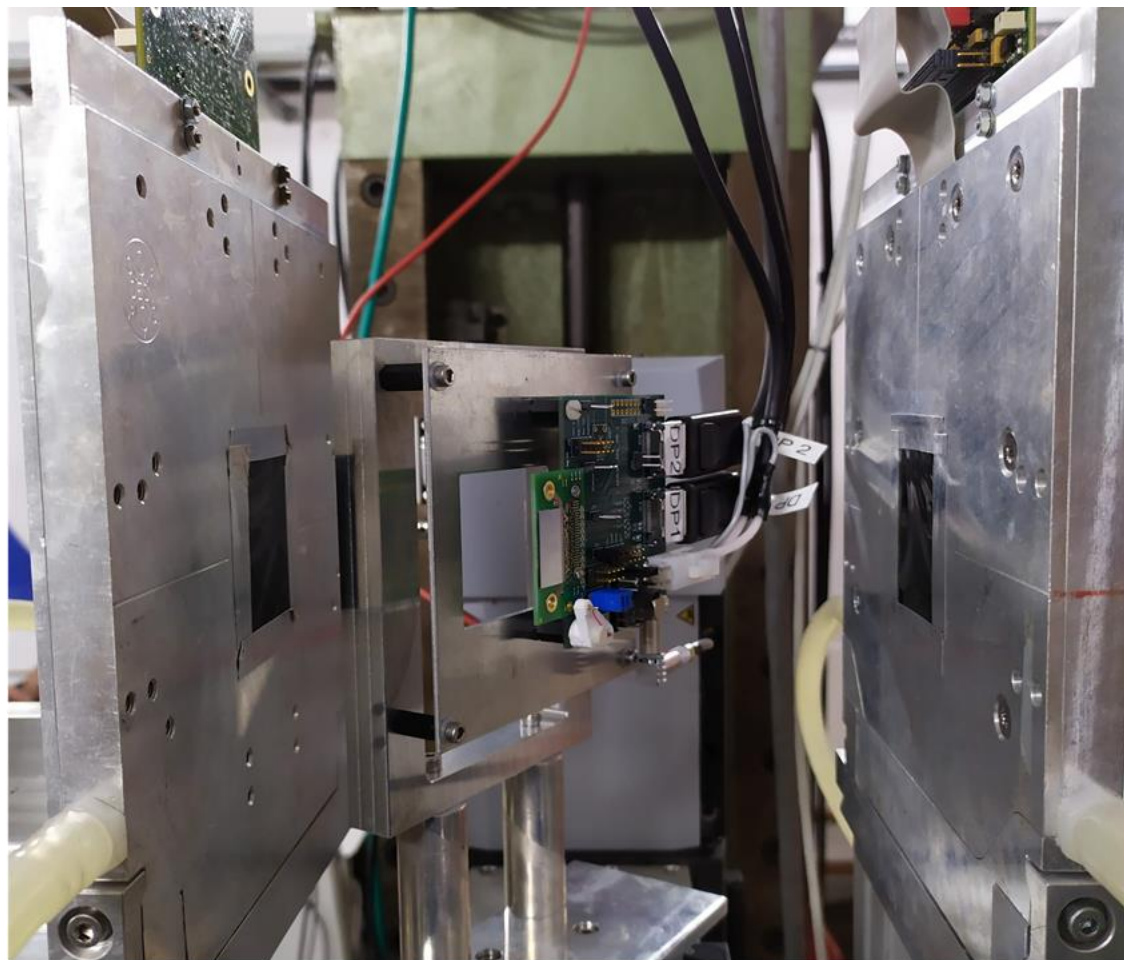
M.Meschini, INFN Firenze



Bonn Card (after irradiation)

6

25×100 μm² setup

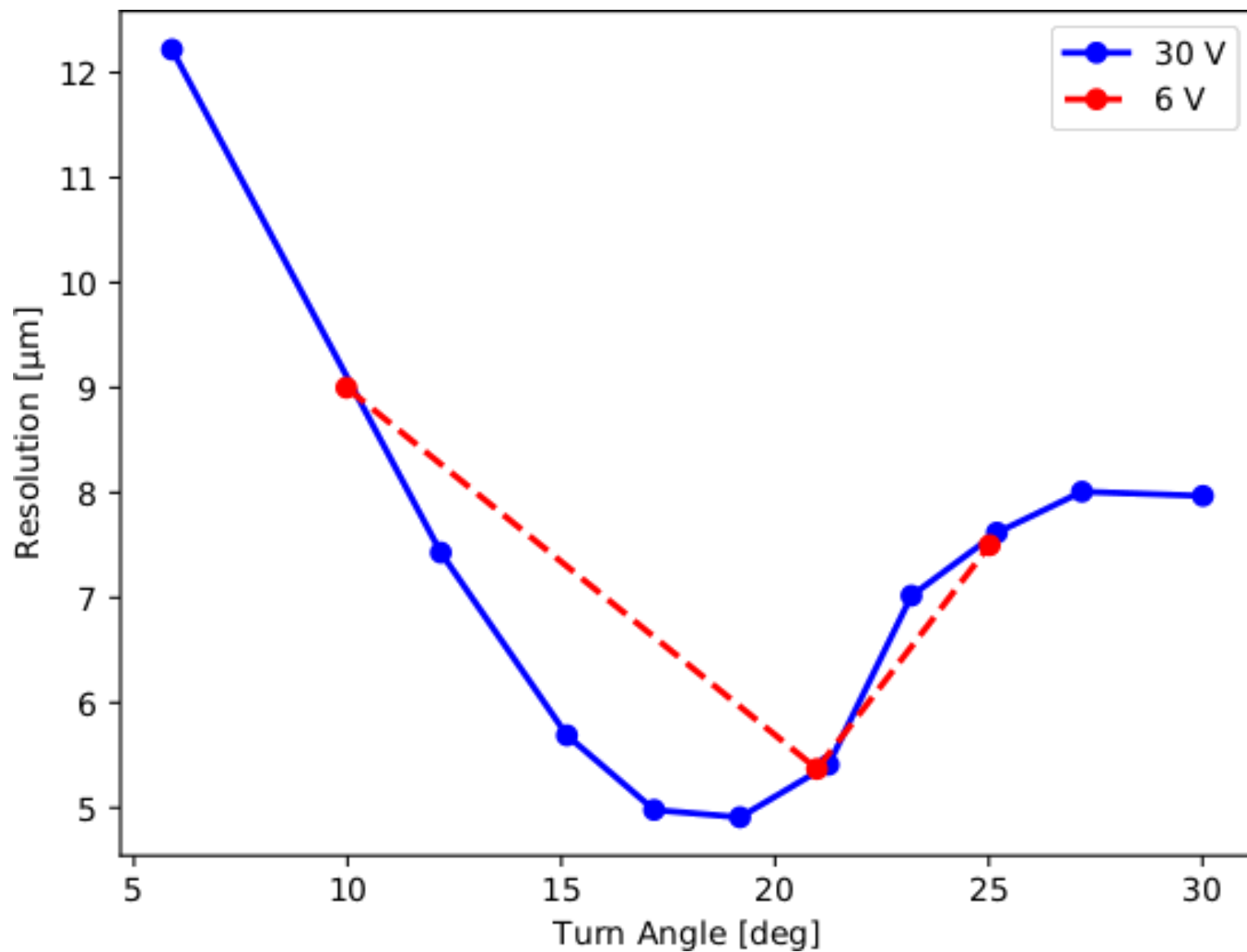


Telescope 4th
plane

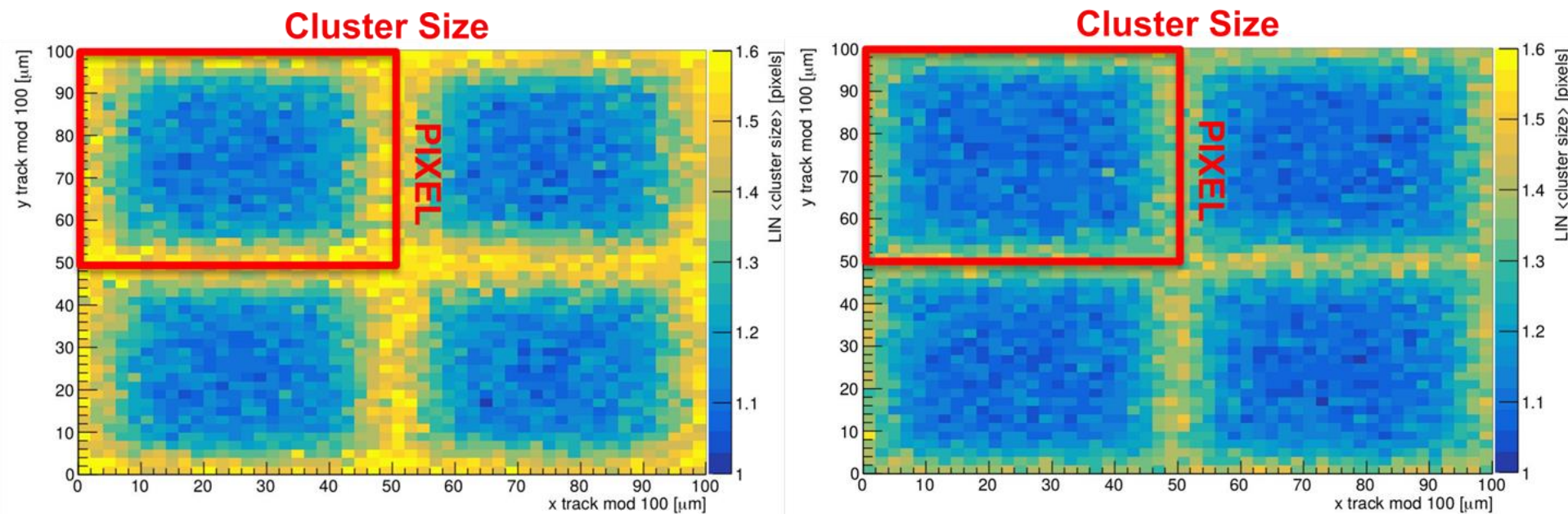
DUT
(on beam, turned)

Telescope 3rd
plane

Rotation wrt bias voltage



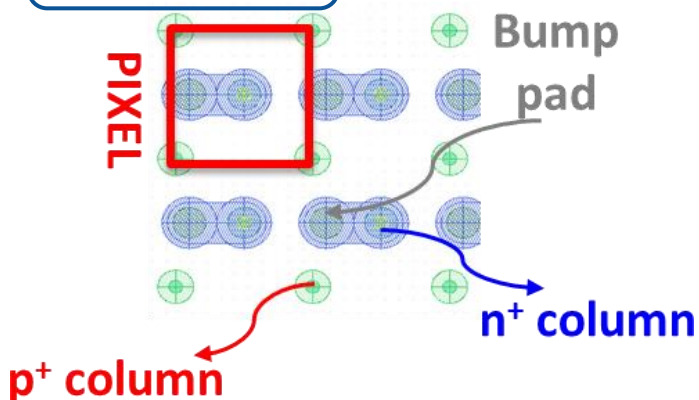
Cluster size: $50 \times 50 \mu\text{m}^2$ (MA)



$$V_{\text{bias}} = 6 \text{ V}$$

Orthogonal beam incidence

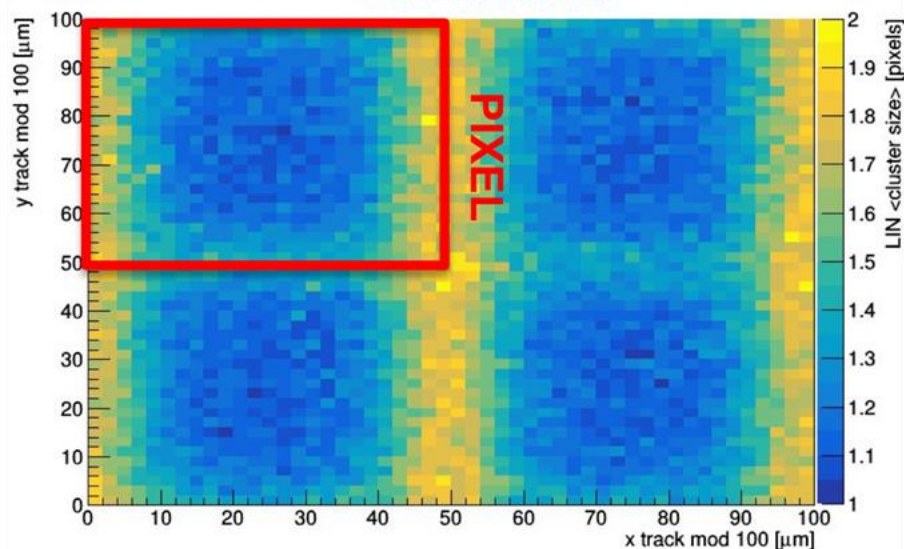
$$V_{\text{bias}} = 30 \text{ V}$$



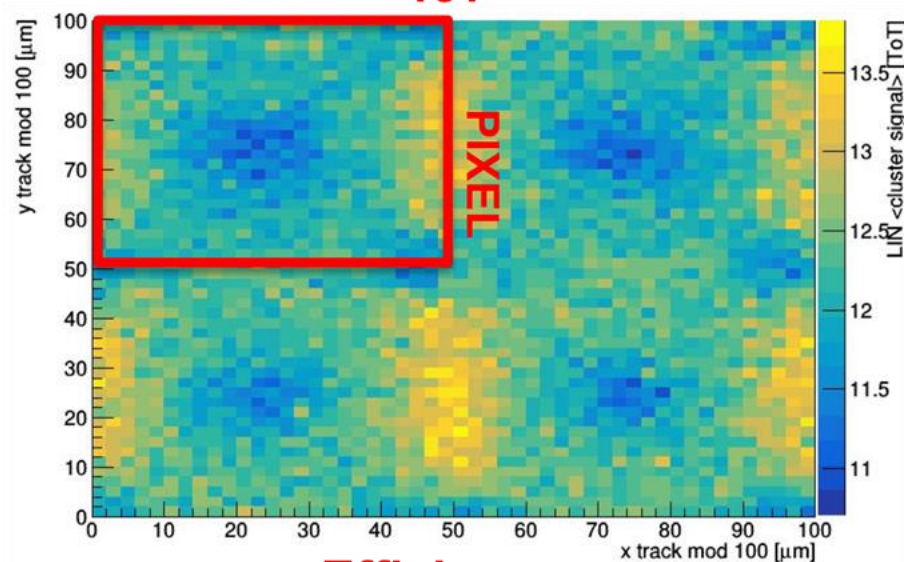
- Cluster size maps for 2×2 pixel grid
- Higher cluster size at lower bias voltage
 - More diffusion \rightarrow more charge sharing between pixels

Cluster size, ToT, Efficiency: $50 \times 50 \mu\text{m}^2$ (MA) @ 6°

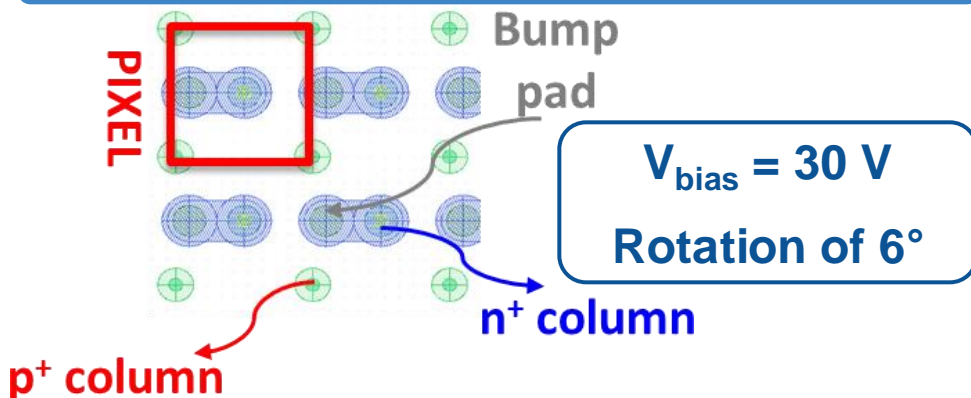
Cluster Size



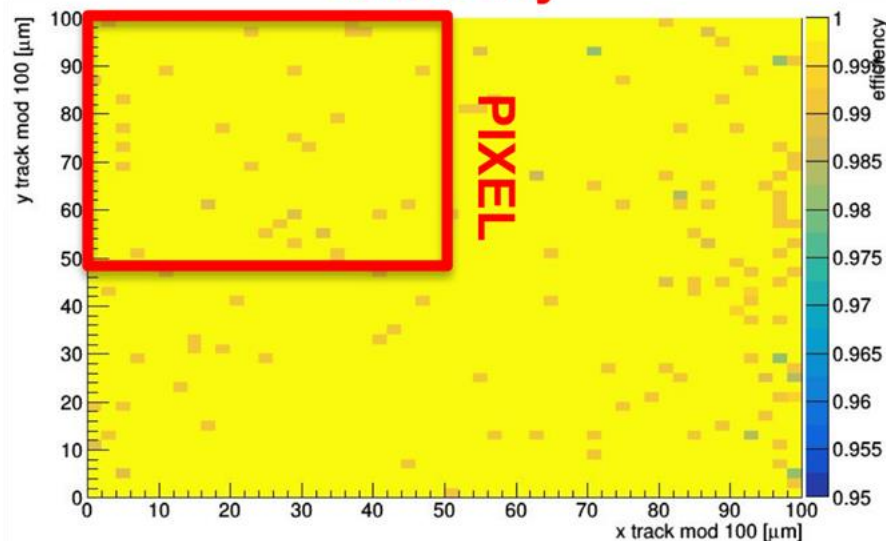
ToT



- Column inefficiencies are no longer there @ 6°
- Charge sharing due to rotation visible from cluster size and ToT maps for 2×2 pixel grid

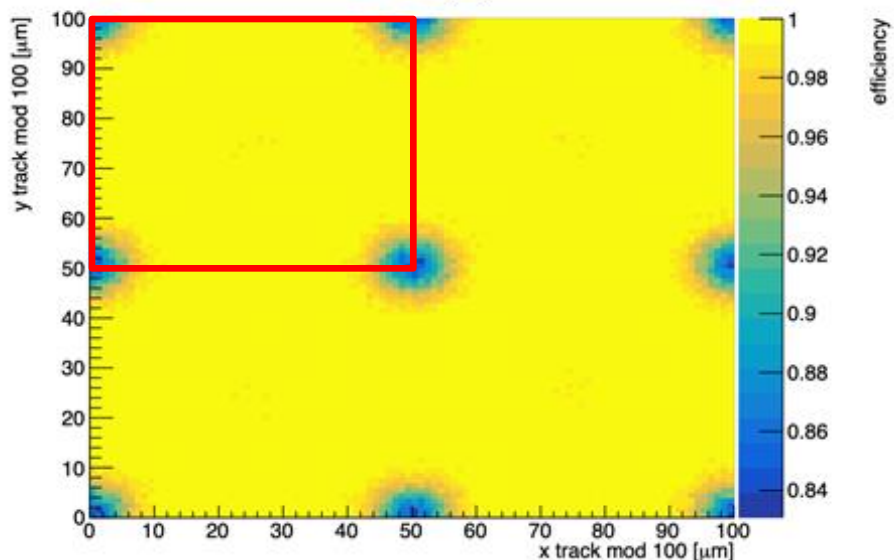


Efficiency

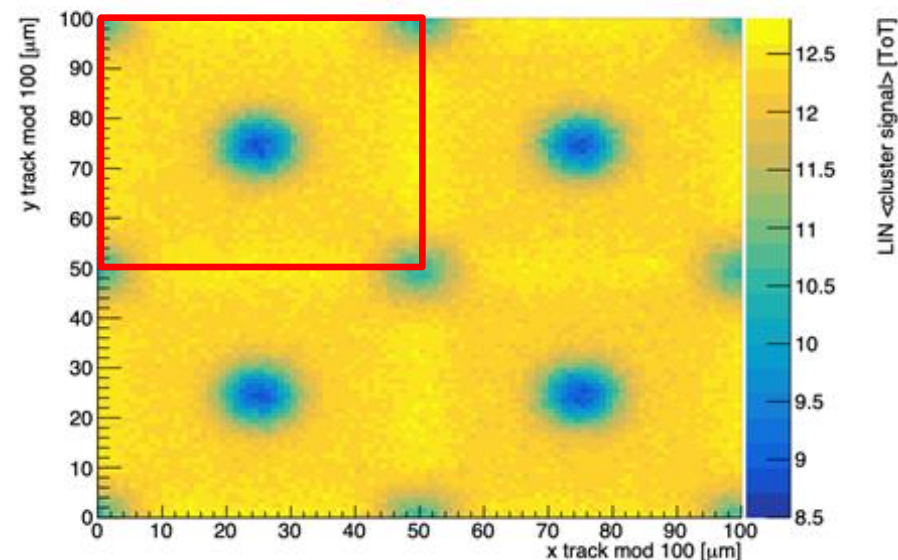


Hit efficiency and ToT: 50×50 μm² (Stepper)

Efficiency per cell

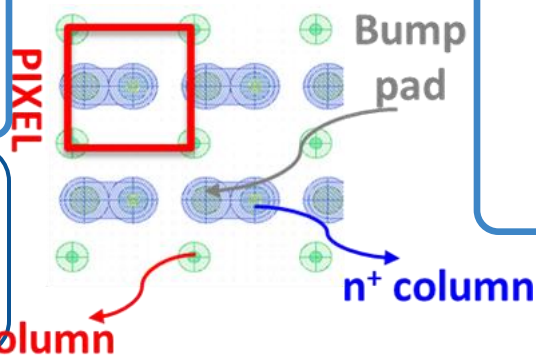


ToT per cell



- Efficiency map for 2×2 pixel grid
- Efficiency drop near p⁺ columns
- High efficiency near n⁺ columns
- Global efficiency > 99%

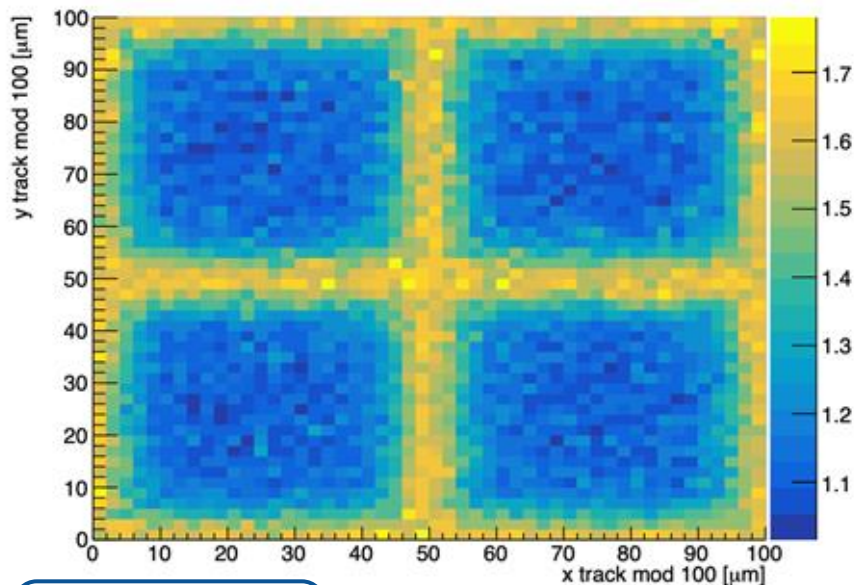
$V_{\text{bias}} = 30 \text{ V}$
 Orthogonal beam incidence
 25M events



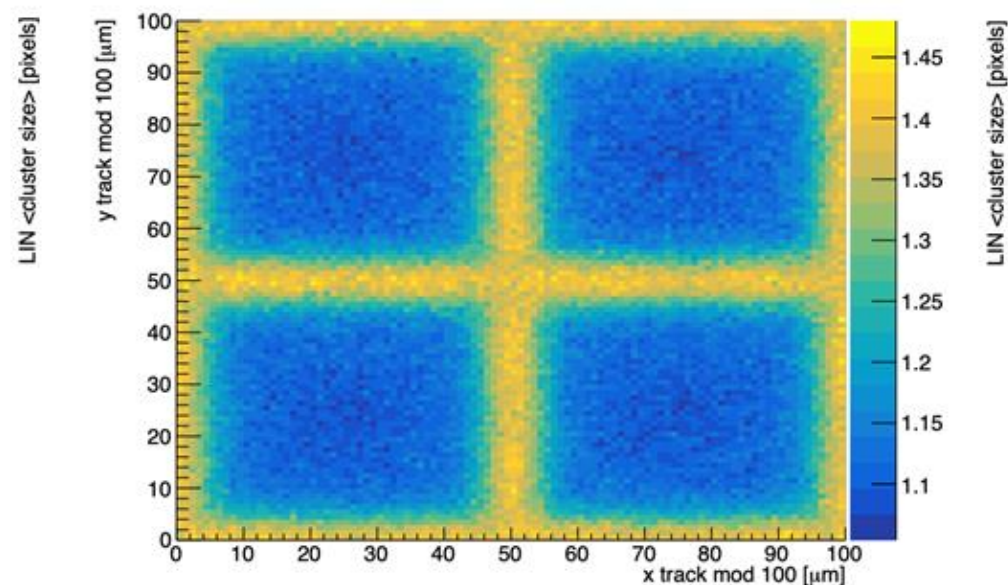
- Tot map for 2×2 pixel grid
- Low average Tot near n⁺ columns
 - Low collected charge (due to passive column), but high efficiency

Cluster size: $50 \times 50 \mu\text{m}^2$ (Stepper)

Cluster size at 6V d



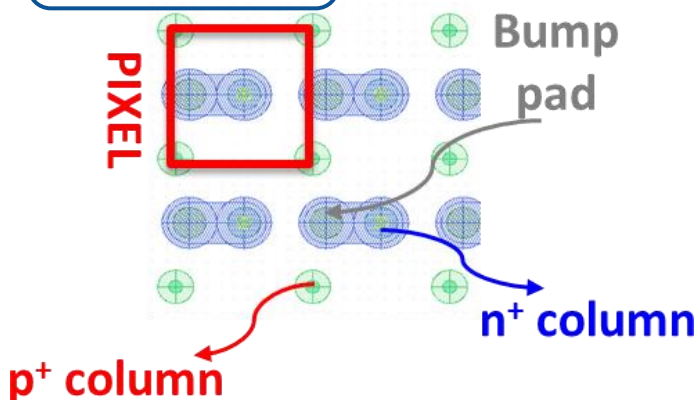
Cluster size at 30V



$V_{\text{bias}} = 6 \text{ V}$
1M events

Orthogonal beam
incidence

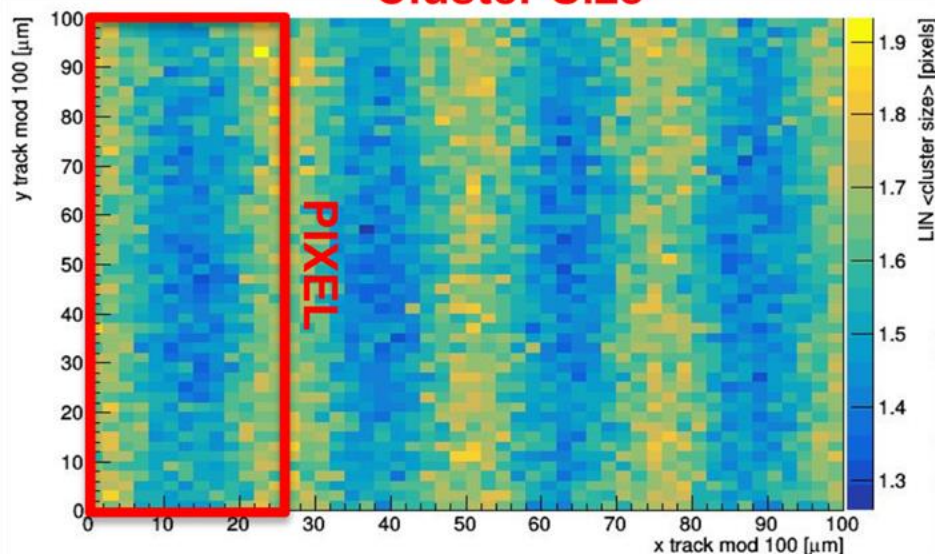
$V_{\text{bias}} = 30 \text{ V}$
25M events



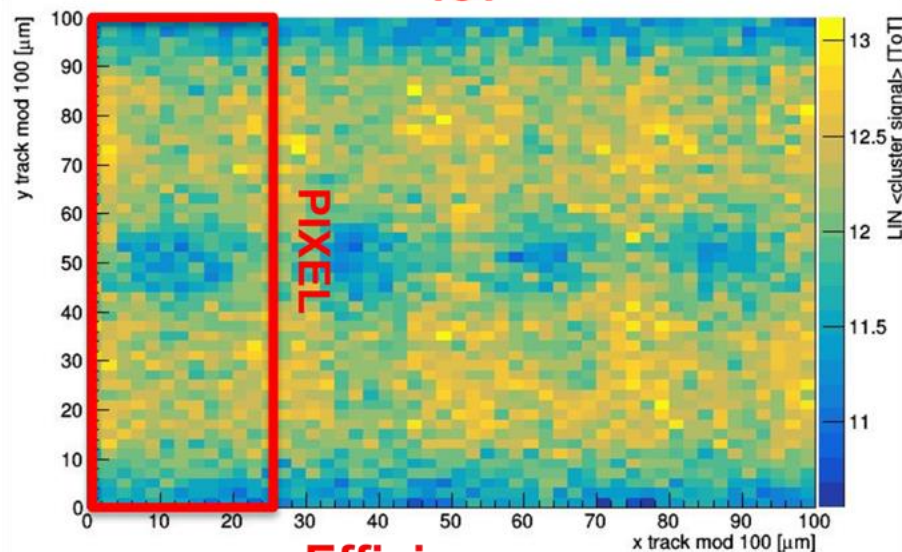
- Cluster size maps for 2×2 pixel grid
- Higher cluster size at lower bias voltage
 - More diffusion \rightarrow more charge sharing between pixels

Cluster size, ToT, Efficiency: $25 \times 100 \mu\text{m}^2$

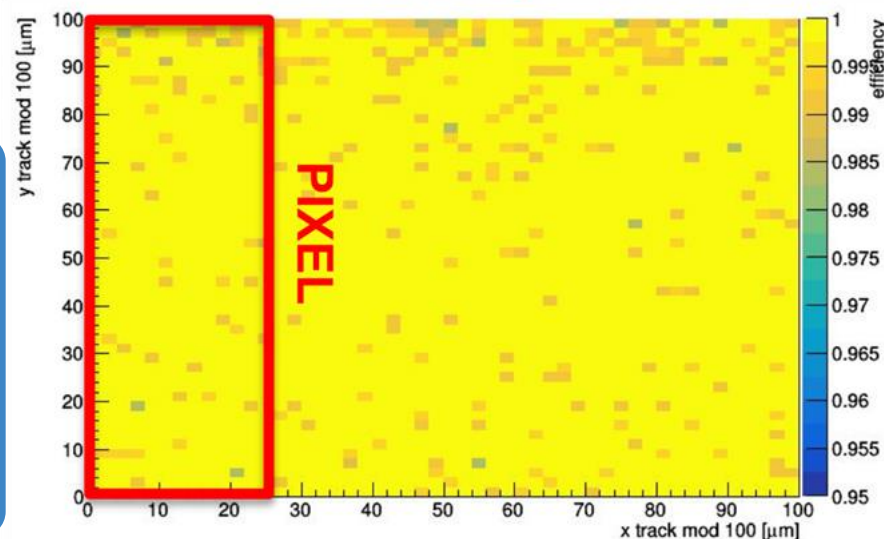
Cluster Size



ToT



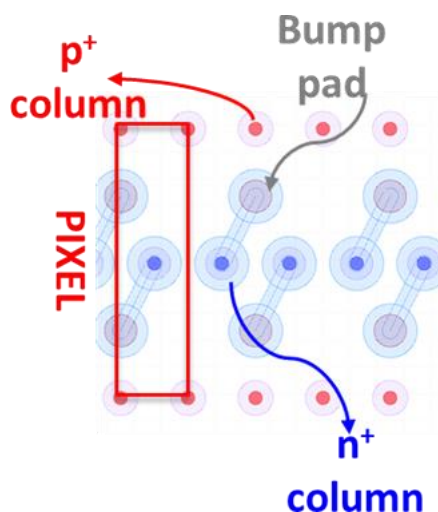
Efficiency



$$V_{\text{bias}} = 30 \text{ V}$$

Rotation of 5°

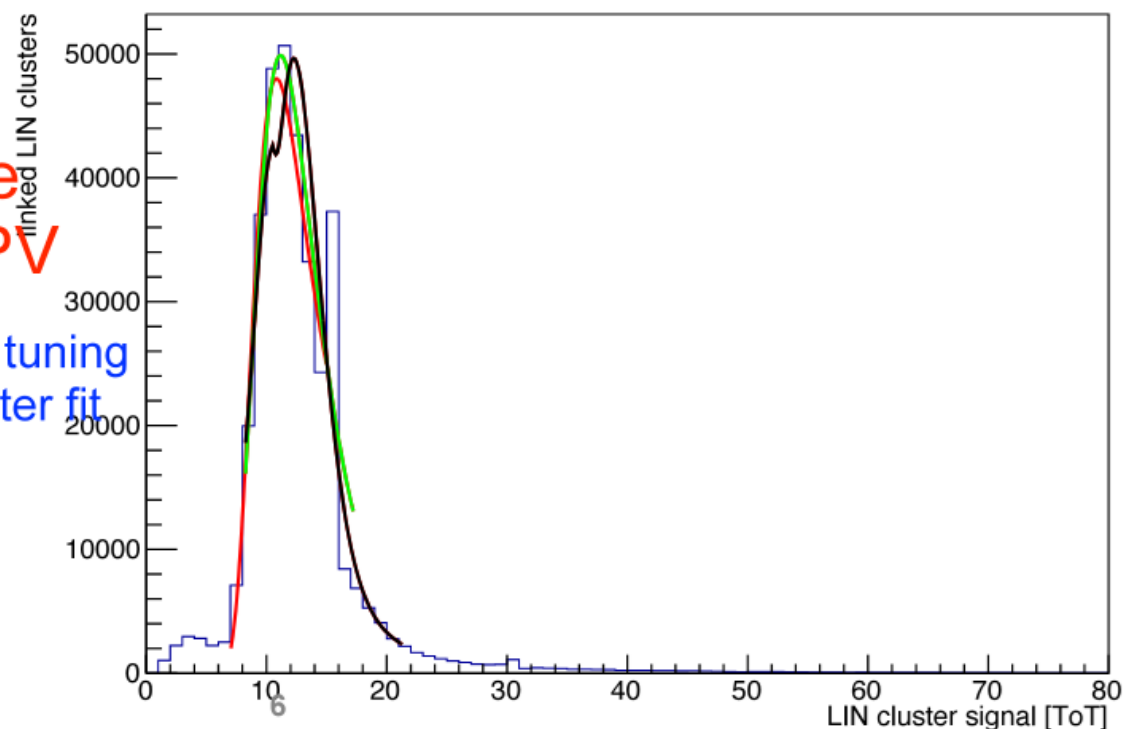
- Column inefficiencies are no longer there @ 5°
- Charge sharing due to rotation visible from cluster size and ToT maps for 4×1 pixel grid



Estimation methods

- We use the full sensor ToT distributions
 - Using clusters associated to a reconstructed track
 - We fit the distribution in several ways and we use the width to feed into the Moyal approx

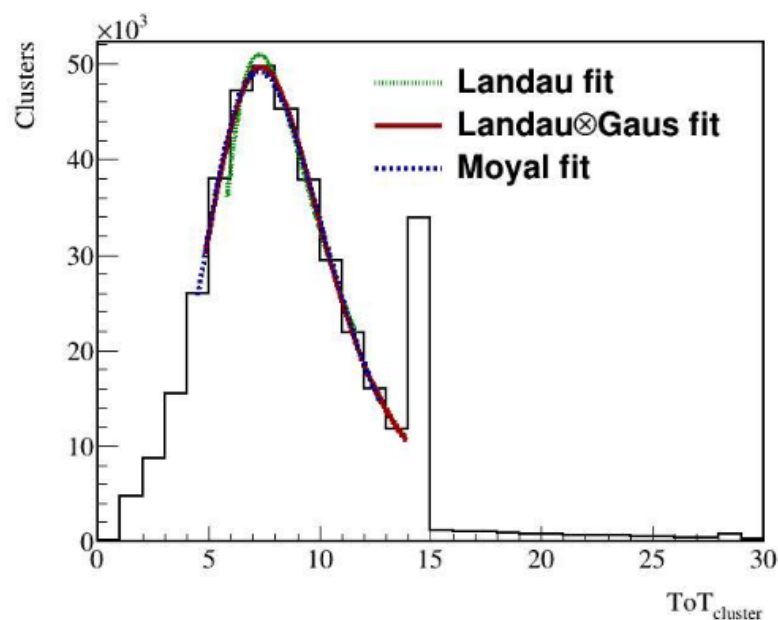
- We then compare the estimated MPV
- In some cases, some tuning is needed to get a better fit



What should we be using?

- But, an analytical distribution could approximate the Landau-Vavilov distribution → **Moyal** distribution

$$f(x) = \frac{1}{\sqrt{2\pi}} \exp \left\{ -\frac{1}{2} \left(\frac{x - \mu}{\sigma} + e^{-\frac{x-\mu}{\sigma}} \right) \right\}$$



- Assuming N-measurements, following the Moyal distribution, the maximization of the Likelihood function gives the MPV (mode) estimator as,

$$\mu = -\sigma \ln \left(\frac{1}{N} \sum_{i=1}^N e^{-\frac{x_i}{\sigma}} \right) = -\sigma \ln \left\langle e^{-\frac{x_i}{\sigma}} \right\rangle$$

→ **This is what it's used in Daniel Pitzl's code**

Moyal, J.E, "Theory of ionization fluctuations", Lond.Edinb.Dubl.Phil.Mag.(1955) 46:374, 263-280

Rotondi, A.; Montagna, P, "Fast Calculation of Vavilov distribution", NIM B47 (1990) 215-22